

INCH-POUND

MIL-M-38510/339D

18 February 2004

SUPERSEDING

MIL-M-38510/339C

2 September 1986

MILITARY SPECIFICATION

MICROCIRCUITS, DIGITAL, BIPOLAR, ADVANCED SCHOTTKY TTL, DATA SELECTORS/MULTIPLEXERS WITH THREE-STATE OUTPUTS, MONOLITHIC SILICON

Reactivated after 18 February 2004 and may be used for either new or existing design acquisition.

This specification is approved for use by all Departments
and Agencies of the Department of Defense.

The requirements for acquiring the product herein shall consist of this specification sheet and MIL-PRF 38535

1. SCOPE

1.1 Scope. This specification covers the detail requirements for monolithic silicon, advanced Schottky TTL, data selectors and multiplexers (three-state) microcircuits. Two product assurance classes and a choice of case outlines and lead finishes are provided for each type and are reflected in the complete part number. For this product, the requirements of MIL-M-38510 have been superseded by MIL-PRF-38535, (see 6.3).

1.2 Part or Identifying Number (PIN). The PIN is in accordance with MIL-PRF-38535, and as specified herein.

1.2.1 Device types. The device types are as follows:

<u>Device type</u>	<u>Circuit</u>
01	8 - input, data selector/multiplexer
02	Dual, 4 - input, data selector/multiplexer
03	Quad, 2 - input, data selector/multiplexer
04	Quad, 2 - input, data selector/multiplexer with inverted output
05	8 - input, data selector/multiplexer with 3 - state outputs
06	Quad, 2 - input, data selector/multiplexer with 3 - state outputs
07	Quad, 2 - input, data selector/multiplexer with 3 - state inverted output
08	Dual, 4 - input, data selector/multiplexer with 3 - state outputs
09	Dual, 4 - input, data selector/multiplexer with inverted outputs
10	Dual, 4 - input, data selector/multiplexer with 3 - state inverted outputs

1.2.2 Device class. The device class is the product assurance level as defined in MIL-PRF-38535.

1.2.3 Case outlines. The case outlines are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
E	GDIP1-T16 or CDIP2-T16	16	Dual-in-line
F	GDFP2-F16 or CDFP3-F16	16	Flat pack
2	CQCC1-N20	20	Square leadless chip carrier

Comments, suggestions, or questions on this document should be addressed to: Commander, Defense Supply Center Columbus, ATTN: DSCC-VAS, 3990 East Broad St., Columbus, OH 43216-5000, or emailed to bipolar@dsccl.dla.mil. Since contact information can change, you may want to verify the currency of this address information using the ASSIST Online database at www.dodssp.daps.mil.

1.3 Absolute maximum ratings.

Supply voltage range	-0.5 V dc to +7.0 V dc
Input voltage range	-1.2 V dc at -18 mA to +7.0 V dc
Storage temperature range	-65° to +150°C
Maximum power dissipation, per device (P_D) ^{1/}	
Device type 01	116 mW
Device type 02	110 mW
Device type 03	127 mW
Device type 04	83 mW
Device type 05	132 mW
Device type 06	127 mW
Device type 07	127 mW
Device type 08	121 mW
Device type 09	110 mW
Device type 10	127 mW
Lead temperature (soldering, 10 seconds)	+300°C
Thermal resistance, junction to case (θ_{JC}):	
Cases E, F, and 2	(See MIL-STD-1835)
Junction temperature (T_J) ^{2/}	175°C

1.4 Recommended operating conditions.

Supply voltage (V_{CC})	4.5 V minimum to 5.5 V maximum
Minimum high level input voltage (V_{IH})	2.0 V dc
Maximum low level input voltage (V_{IL})	0.8 V dc
Case operating temperature range (T_C)	-55° to +125°C

2. APPLICABLE DOCUMENTS

2.1 General. The documents listed in this section are specified in sections 3, 4, or 5 of this specification. This section does not include documents cited in other sections of this specification or recommended for additional information or as examples. While every effort has been made to ensure the completeness of this list, document users are cautioned that they must meet all specified requirements of documents cited in sections 3, 4, or 5 of this specification, whether or not they are listed.

2.2 Government documents.

2.2.1 Specifications and Standards. The following specifications and standards form a part of this specification to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

DEPARTMENT OF DEFENSE SPECIFICATIONS

MIL-PRF-38535 - Integrated Circuits (Microcircuits) Manufacturing, General Specification for.

DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard for Microelectronics.
MIL-STD-1835 - Interface Standard Electronic Component Case Outlines

(Copies of these documents are available online at <http://assist.daps.dla.mil;quicksearch/> or www.dodssp.daps.mil or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

^{1/} Must withstand the added P_D due to short-circuit test (e.g., I_{OS}).

^{2/} Maximum junction temperature shall not be exceeded except in accordance with allowable short duration burn-in screening condition in accordance with MIL-PRF-38535.

2.3 Order of precedence. In the event of a conflict between the text of this specification and the references cited herein, the text of this document takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 Qualification. Microcircuits furnished under this specification shall be products that are manufactured by a manufacturer authorized by the qualifying activity for listing on the applicable qualified manufacturers list before contract award (see 4.3 and 6.4).

3.2 Item requirements. The individual item requirements shall be in accordance with MIL-PRF-38535 and as specified herein or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.

3.3 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535 and herein.

3.3.1 Terminal connections and pin assignments. The terminal connections and pin assignments shall be as specified on figure 1.

3.3.2 Logic diagrams. The logic diagrams shall be as specified on figure 2.

3.3.3 Truth tables. The truth tables shall be as specified on figure 3.

3.3.4 Schematic circuits. The schematic circuits shall be maintained by the manufacturer and made available to the qualifying activity and the preparing activity upon request.

3.3.5 Case outlines. The case outlines shall be as specified in 1.2.3.

3.4 Lead material and finish. The lead material and finish shall be in accordance with MIL-PRF-38535 (see 6.6).

3.5 Electrical performance characteristics. The electrical performance characteristics are as specified in table I, and apply over the full recommended case operating temperature range, unless otherwise specified.

3.6 Electrical test requirements. The electrical test requirements for each device class shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table III.

3.7 Marking. Marking shall be in accordance with MIL-PRF-38535.

3.8 Microcircuit group assignment. The devices covered by this specification shall be in microcircuit group number 11 (see MIL-PRF-38535, appendix A).

4. VERIFICATION

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not effect the form, fit, or function as described herein.

4.2 Screening. Screening shall be in accordance with MIL-PRF-38535 and shall be conducted on all devices prior to qualification and quality conformance inspection. The following additional criteria shall apply:

- a. The burn-in test duration, test condition, and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document control by the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.
- b. Interim and final electrical test parameters shall be as specified in table II, except interim electrical parameters test prior to burn-in is optional at the discretion of the manufacturer.
- c. Additional screening for space level product shall be as specified in MIL-PRF-38535.

4.3 Qualification inspection. Qualification inspection shall be in accordance with MIL-PRF-38535.

4.4 Technology Conformance inspection (TCI). Technology conformance inspection shall be in accordance with MIL-PRF-38535 and herein for groups A, B, C, and D inspections (see 4.4.1 through 4.4.4).

4.4.1 Group A inspection. Group A inspection shall be in accordance with table III of MIL-PRF-38535 and as follows:

- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, and 6 shall be omitted.

4.4.2 Group B inspection. Group B inspection shall be in accordance with table II of MIL-PRF-38535.

4.4.3 Group C inspection. Group C inspection shall be in accordance with table IV of MIL-PRF-38535 and as follows:

- a. End-point electrical parameters shall be as specified in table II herein.
- b. The steady-state life test duration, test condition, and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document control by the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.

4.4.4 Group D inspection. Group D inspection shall be in accordance with table V of MIL-PRF-38535. End-point electrical parameters shall be as specified in table II herein.

4.5 Methods of inspection. Methods of inspection shall be specified as follows:

4.5.1 Voltage and current. All voltages given are referenced to the microcircuit ground terminal. Currents given are conventional and positive when flowing into the referenced terminal.

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions $-55^{\circ}\text{C} \leq T_C \leq +125^{\circ}\text{C}$		Device type	Limits		Unit
					Min	Max	
High level output voltage	V_{OH}	$V_{CC} = 4.5\text{ V},$ $V_{IL} = 0.8\text{ V},$ $V_{IH} = 2.0\text{ V}$	$I_{OH} = -1.0\text{ mA}$	01, 02, 03, 04, 09	2.5		V
			$I_{OH} = -3.0\text{ mA}$	05, 06, 07, 08, 10	2.4		V
Low level output voltage	V_{OL}	$V_{CC} = 4.5\text{ V}, I_{OL} = 20\text{ mA},$ $V_{IH} = 2.0\text{ V}, V_{IL} = 0.8\text{ V}$		All		0.5	V
Input clamp voltage	V_{IC}	$V_{CC} = 4.5\text{ V}, I_{IN} = -18\text{ mA},$ $T_C = +25^{\circ}\text{C}$		All		-1.2	V
High level input current	I_{IH1}	$V_{CC} = 5.5\text{ V}, V_{IH} = 2.7\text{ V}$		All		20	μA
	I_{IH2}	$V_{CC} = 5.5\text{ V}, V_{IH} = 7.0\text{ V}$		All		100	μA
Low level input current	I_{IL}	$V_{CC} = 5.5\text{ V}, V_{IL} = 0.5\text{ V}$		All	-0.3	-0.60	mA
Short circuit output current <u>1/</u>	I_{OS}	$V_{CC} = 5.5\text{ V}, V_{OS} = 0\text{ V}$		All	-60	-150	mA
Output drive	I_{OD}	$V_{CC} = 4.5\text{ V},$		01, 04, 09	60		mA
				02, 03, 05, 06, 07, 08, 10	35		mA
Supply current	I_{CC}	$V_{CC} = 5.5\text{ V}, V_{OS} = 0\text{ V}$		01		21	mA
				02		20	mA
				03		23	mA
				04		15	mA
				05		22	mA
High level supply current	I_{CCH}	$V_{CC} = 5.5\text{ V}$		06		15	mA
				07		9.5	mA
				08		16	mA
				09		14	mA
				10		14	mA
Low level supply current	I_{CCL}	$V_{CC} = 5.5\text{ V}$		06		22	mA
				07		23	mA
				08		23	mA
				09		20	mA
				10		20	mA

1/ Not more than one output should be shorted at a time.

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C ≤ T _C ≤ +125°C	Device type	Limits		Unit
				Min	Max	
Off state supply current	I _{CCZ}	V _{CC} = 5.5 V Outputs disabled	05		24	mA
			06		23	mA
			07		17	mA
			08		23	mA
			10		23	mA
Off state output leakage current	I _{OZH}	V _{CC} = 5.5 V, V _{ZH} = 2.7 V	05, 06, 07, 08, 10		50	μA
	I _{OZL}	V _{CC} = 5.5 V, V _{ZL} = 0.5 V			-50	μA
Propagation delay time, low to high level, data to Z output	t _{PLH1}	V _{CC} = 5.5 V (see figure 4)	01	2.5	8.5	ns
			02	2.5	9.0	ns
			03	2.5	7.5	ns
			05	2.5	9.0	ns
			06	2.0	7.0	ns
			08	2.5	9.0	ns
Propagation delay time, low to high level, data to \bar{Z} output	t _{PLH2}	V _{CC} = 5.5 V (see figure 4)	01	2.5	7.5	ns
			04	2.5	8.5	ns
			05	2.5	8.5	ns
			07	2.0	7.5	ns
			09	2.0	9.0	ns
			10	1.5	9.0	ns
Propagation delay time, low to high level, select to Z output	t _{PLH3}	V _{CC} = 5.5 V (see figure 4)	01	4.5	13.5	ns
			02	4.5	14.0	ns
			03	4.0	12.0	ns
			05	3.5	14.0	ns
			06	3.5	11.5	ns
			08	3.5	15.0	ns
Propagation delay time, low to high level, select to \bar{Z} output	t _{PLH4}	V _{CC} = 5.5 V (see figure 4)	01	3.5	11.5	ns
			04	3.0	10.5	ns
			05	3.5	11.5	ns
			07	3.0	9.5	ns
			09	3.5	14.5	ns
			10	4.0	16.0	ns
Propagation delay time, low to high level, enable to Z output	t _{PLH5}	V _{CC} = 5.5 V (see figure 4)	01	4.0	12.0	ns
			02	4.5	11.5	ns
			03	5.0	13.0	ns
Propagation delay time, low to high level, enable to \bar{Z} output	t _{PLH6}	V _{CC} = 5.5 V (see figure 4)	01	3.0	7.5	ns
			04	2.5	8.0	ns
			09	3.5	17.0	ns

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C ≤ T _C ≤ +125°C	Device type	Limits		Unit
				Min	Max	
Propagation delay time, high to low level, data to Z output	t _{PHL1}	V _{CC} = 5.5 V (see figure 4)	01	3.5	9.0	ns
			02	2.5	8.0	ns
			03	1.5	7.5	ns
			05	3.5	9.0	ns
			06	1.5	7.0	ns
			08	2.5	8.0	ns
Propagation delay time, high to low level, data to \bar{Z} output	t _{PHL2}	V _{CC} = 5.5 V (see figure 4)	01	1.5	6.0	ns
			04	1.5	5.0	ns
			05	1.0	6.0	ns
			07	1.0	6.0	ns
			09	1.5	7.5	ns
			10	1.5	7.5	ns
Propagation delay time, high to low level, select to Z output	t _{PHL3}	V _{CC} = 5.5 V (see figure 4)	01	4.0	9.5	ns
			02	3.5	11.0	ns
			03	3.0	9.0	ns
			05	3.0	10.5	ns
			06	2.5	9.0	ns
			08	2.5	11.0	ns
Propagation delay time, high to low level, select to \bar{Z} output	t _{PHL4}	V _{CC} = 5.5 V (see figure 4)	01	3.0	8.0	ns
			04	2.5	8.0	ns
			05	3.2	8.0	ns
			07	2.5	9.0	ns
			09	3.5	15.0	ns
			10	4.0	14.0	ns
Propagation delay time, high to low level, enable to Z output	t _{PHL5}	V _{CC} = 5.5 V (see figure 4)	01	3.0	8.0	ns
			02	2.5	9.0	ns
			03	2.5	7.5	ns
Propagation delay time, high to low level, enable to \bar{Z} output	t _{PHL6}	V _{CC} = 5.5 V (see figure 4)	01	2.5	6.5	ns
			04	2.0	8.5	ns
			09	3.0	13.0	ns
Propagation delay time, low level to off state, output enable to Z output	t _{PLZ5}	V _{CC} = 5.5 V (see figure 4)	05	1.0	5.5	ns
			06	2.0	8.5	ns
			08	2.0	8.0	ns
Propagation delay time, low level to off state, output enable to \bar{Z} output	t _{PLZ6}	V _{CC} = 5.5 V (see figure 4)	05	1.0	5.0	ns
			07	2.0	8.5	ns
			10	2.0	8.5	ns

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C ≤ T _C ≤ +125°C	Device type	Limits		Unit
				Min	Max	
Propagation delay time, high level to off state, output enable to Z output	t _{PHZ5}	V _{CC} = 5.5 V (see figure 4)	05	2.0	5.5	ns
			06	2.0	7.0	ns
			08	2.0	6.5	ns
Propagation delay time, high level to off state, output enable to \bar{Z} output	t _{PHZ6}		05	2.0	6.0	ns
			07	1.5	7.0	ns
			10	2.0	6.5	ns
Propagation delay time, off state to low level output enable to Z output	t _{PZL5}		05	2.5	9.0	ns
			06	2.5	9.0	ns
			08	2.5	10.0	ns
Propagation delay time, off state to low level output enable to \bar{Z} output	t _{PZL6}		05	2.5	7.5	ns
			07	2.5	9.0	ns
			10	3.0	15.5	ns
Propagation delay time, off state to high level output enable to Z output	t _{PZH5}	05	3.0	8.5	ns	
		06	2.0	8.0	ns	
		08	2.5	10.0	ns	
Propagation delay time, off state to high level output enable to \bar{Z} output	t _{PZH6}	05	2.0	7.0	ns	
		07	2.0	8.0	ns	
		10	3.0	11.0	ns	

TABLE II. Electrical test requirements.

MIL-PRF-38535 test requirements	Subgroups (see table III)	
	Class S devices	Class B devices
Interim electrical parameters	1	1
Final electrical test parameters	1*, 2, 3, 7, 9, 10, 11	1*, 2, 3, 7, 9
Group A test requirements	1, 2, 3, 7, 8, 9, 10, 11	1, 2, 3, 7, 8, 9, 10, 11
Group B electrical test parameters when using the method 5005 QCI option	1, 2, 3, 7, 8, 9, 10, 11	N/A
Group C end-point electrical parameters	1, 2, 3, 7, 8, 9, 10, 11	1, 2, 3
Group D end-point electrical parameters	1, 2, 3	1, 2, 3

*PDA applies to subgroup 1.

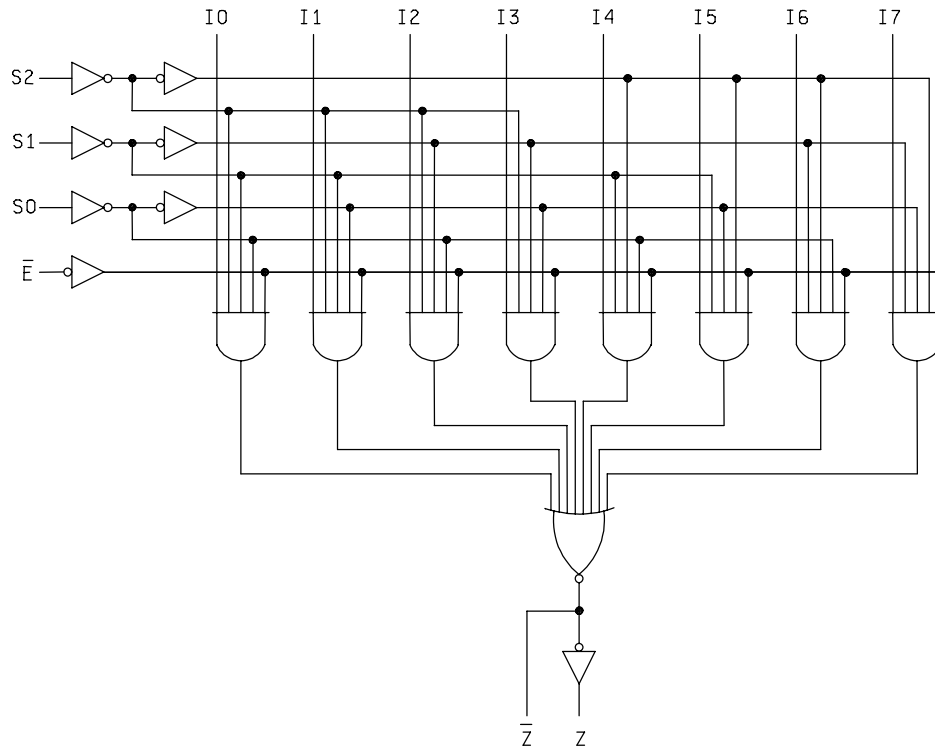
Terminal number	Terminal assignments									
	Device type 01		Device type 02		Device type 03		Device type 04		Device type 05	
	Cases E and F	Case 2	Cases E and F	Case 2	Cases E and F	Case 2	Cases E and F	Case 2	Cases E and F	Case 2
1	I3	N/C	$\bar{E} a$	N/C	S	N/C	S	N/C	I3	N/C
2	I2	I3	S1	$\bar{E} a$	I0a	S	I0a	S	I2	I3
3	I1	I2	I3a	S1	I1a	I0a	I1a	I0a	I1	I2
4	I0	I1	I2a	I3a	Za	I1a	$\bar{Z} a$	I1a	I0	I1
5	Z	I0	I1a	I2a	I0b	Za	I0b	$\bar{Z} a$	Z	I0
6	\bar{Z}	N/C	I0a	N/C	I1b	N/C	I1b	N/C	\bar{Z}	N/C
7	\bar{E}	Z	Za	I1a	Zb	I0b	$\bar{Z} b$	I0b	$\bar{Q}E$	Z
8	GND	\bar{Z}	GND	I0a	GND	I1b	GND	I1b	GND	\bar{Z}
9	S2	\bar{E}	Zb	Za	Zd	Zb	$\bar{Z} d$	$\bar{Z} b$	S2	$\bar{Q}E$
10	S1	GND	I0b	GND	I1d	GND	I1d	GND	S1	GND
11	S0	N/C	I1b	N/C	I0d	N/C	I0d	N/C	S0	N/C
12	I7	S2	I2b	Zb	Zc	Zd	$\bar{Z} c$	$\bar{Z} d$	I7	S2
13	I6	S1	I3b	I0b	I1c	I1d	I1c	I1d	I6	S1
14	I5	S0	S0	I1b	I0c	I0d	I0c	I0d	I5	S0
15	I4	I7	$\bar{E} b$	I2b	\bar{E}	Zc	\bar{E}	$\bar{Z} c$	I4	I7
16	V _{CC}	N/C	V _{CC}	N/C	V _{CC}	N/C	V _{CC}	N/C	V _{CC}	N/C
17		I6		I3b		I1c		I1c		I6
18		I5		S0		I0c		I0c		I5
19		I4		$\bar{E} b$		\bar{E}		\bar{E}		I4
20		V _{CC}		V _{CC}		V _{CC}		V _{CC}		V _{CC}

FIGURE 1. Terminal connections.

Terminal number	Terminal assignments									
	Device type 06		Device type 07		Device type 08		Device type 09		Device type 10	
	Cases E and F	Case 2	Cases E and F	Case 2	Cases E and F	Case 2	Cases E and F	Case 2	Cases E and F	Case 2
1	S	N/C	S	N/C	$\overline{OE} a$	N/C	$\overline{E} a$	N/C	$\overline{OE} a$	N/C
2	I0a	S	I0a	S	S1	$\overline{OE} a$	S1	$\overline{E} a$	S1	$\overline{OE} a$
3	I1a	I0a	I1a	I0a	I3a	S1	I3a	S1	I3a	S1
4	Za	I1a	$\overline{Z} a$	I1a	I2a	I3a	I2a	I3a	I2a	I3a
5	I0b	Za	I0b	$\overline{Z} a$	I1a	I2a	I1a	I2a	I1a	I2a
6	I1b	N/C	I1b	N/C	I0a	N/C	I0a	N/C	I0a	N/C
7	Zb	I0b	$\overline{Z} b$	I0b	Za	I1a	$\overline{Z} a$	I1a	$\overline{Z} a$	I1a
8	GND	I1b	GND	I1b	GND	I0a	GND	I0a	GND	I0a
9	Zd	Zb	$\overline{Z} d$	$\overline{Z} b$	Zb	Za	$\overline{Z} b$	$\overline{Z} a$	$\overline{Z} b$	$\overline{Z} a$
10	I1d	GND	I1d	GND	I0b	GND	I0b	GND	I0b	GND
11	I0d	N/C	I0d	N/C	I1b	N/C	I1b	N/C	I1b	N/C
12	Zc	Zd	$\overline{Z} c$	$\overline{Z} d$	I2b	Zb	I2b	$\overline{Z} b$	I2b	$\overline{Z} b$
13	I1c	I1d	I1c	I1d	I3b	I0b	I3b	I0b	I3b	I0b
14	I0c	I0d	I0c	I0d	S0	I1b	S0	I1b	S0	I1b
15	\overline{OE}	Zc	\overline{OE}	$\overline{Z} c$	$\overline{OE} b$	I2b	$\overline{E} b$	I2b	$\overline{OE} b$	I2b
16	V _{CC}	N/C	V _{CC}	N/C	V _{CC}	N/C	V _{CC}	N/C	V _{CC}	N/C
17		I1c		I1c		I3b		I3b		I3b
18		I0c		I0c		S0		S0		S0
19		\overline{OE}		\overline{OE}		$\overline{OE} b$		$\overline{E} b$		$\overline{OE} b$
20		V _{CC}		V _{CC}		V _{CC}		V _{CC}		V _{CC}

FIGURE 1. Terminal connections - Continued.

DEVICE TYPE 01



DEVICE TYPE 02

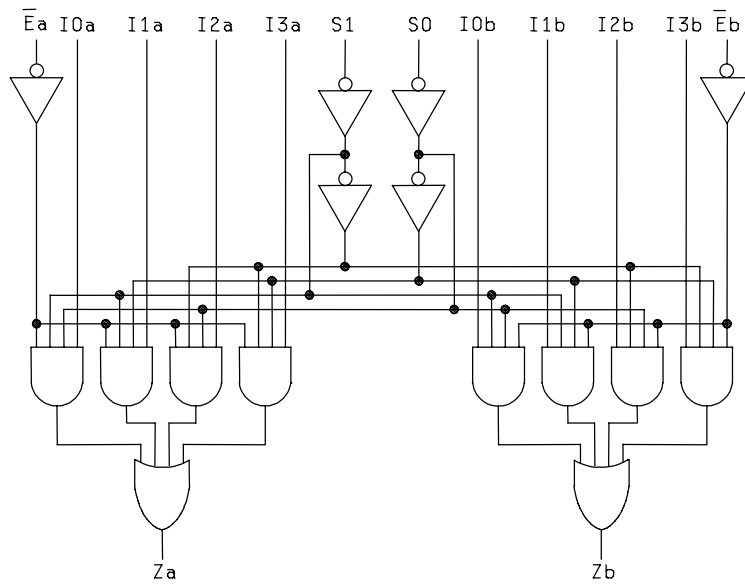
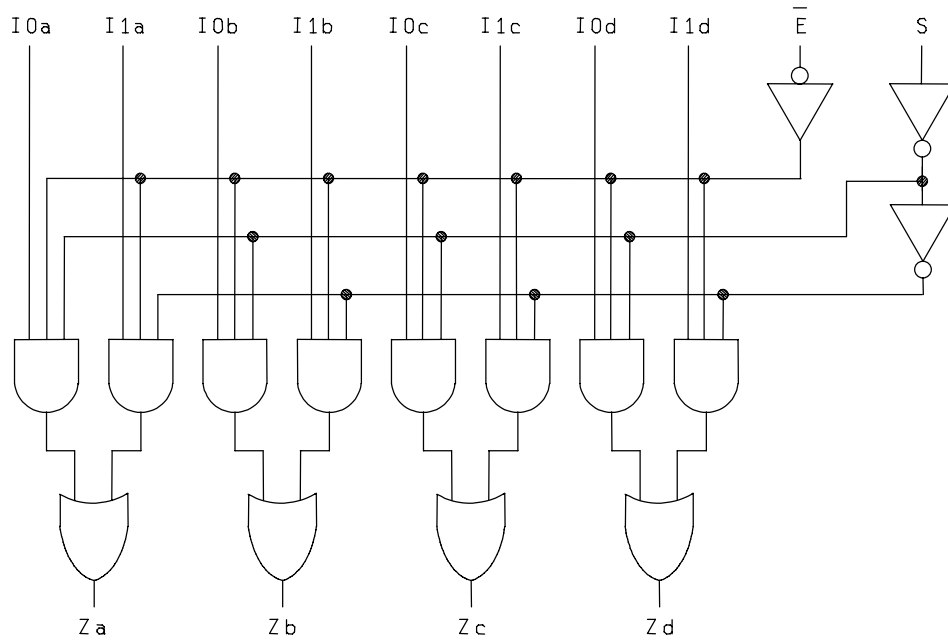


FIGURE 2. Logic diagrams.

DEVICE TYPE 03



DEVICE TYPE 04

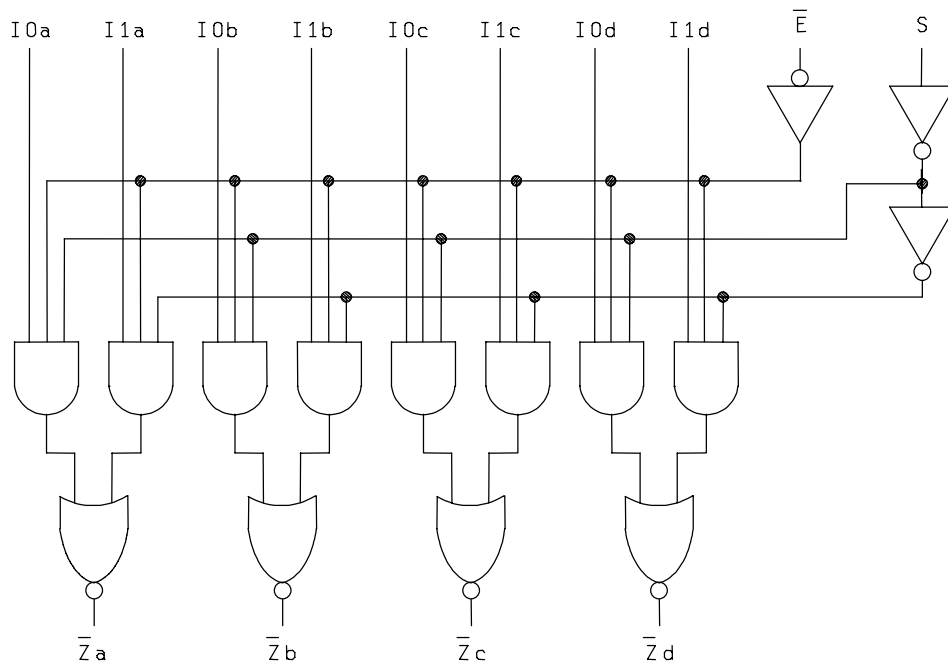
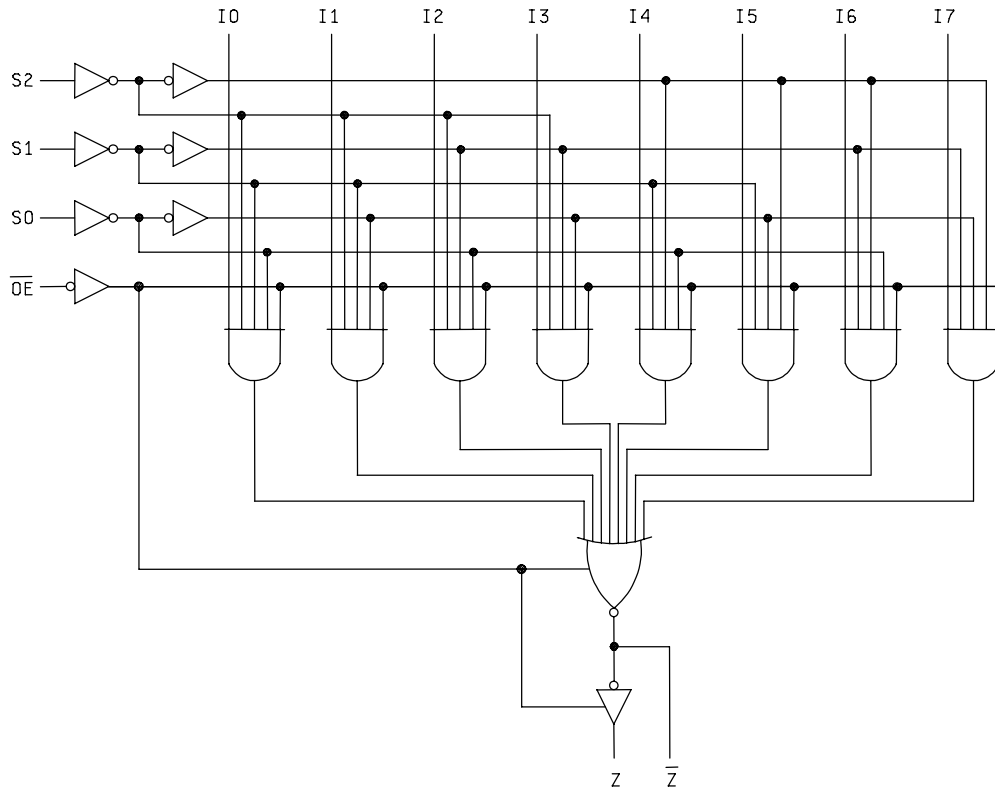


FIGURE 2. Logic diagrams - Continued.

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DEVICE TYPE 05



DEVICE TYPE 06

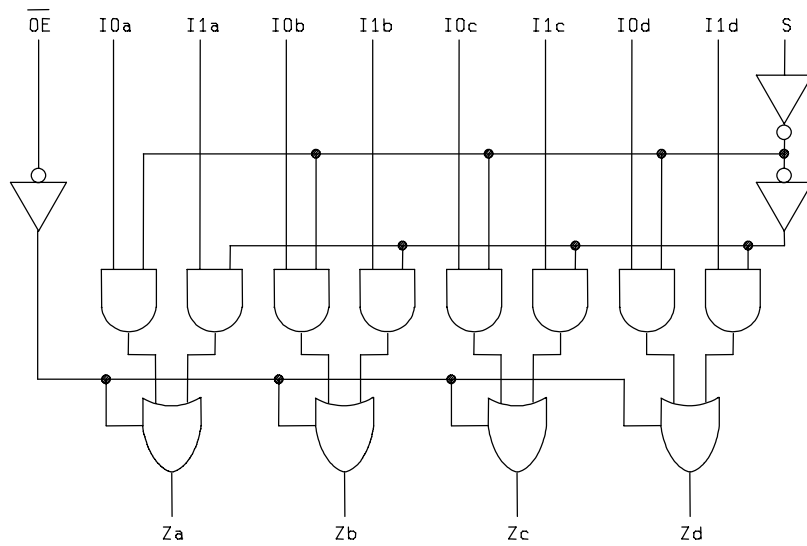
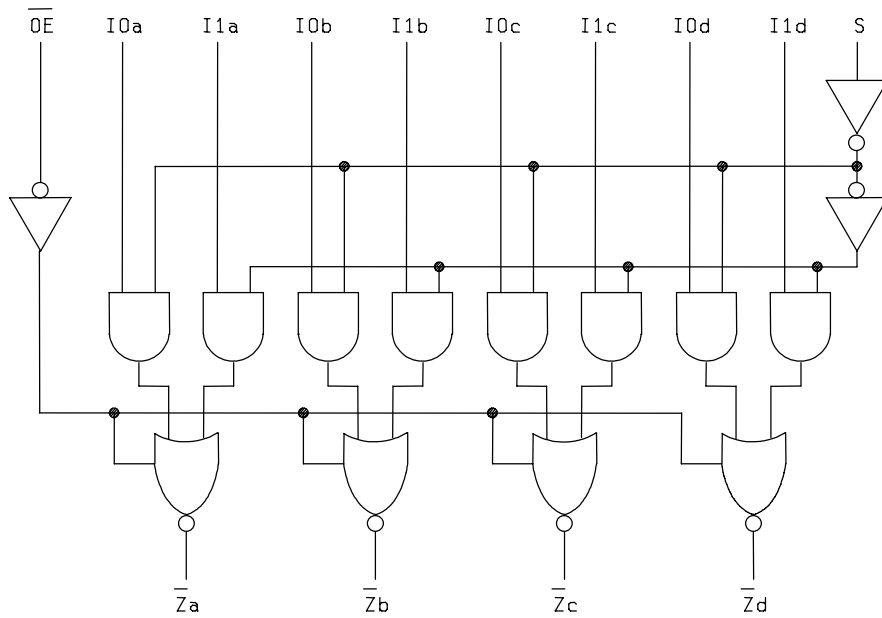


FIGURE 2. Logic diagrams - Continued.

MIL-M-38510/339D

DEVICE TYPE 07



DEVICE TYPE 08

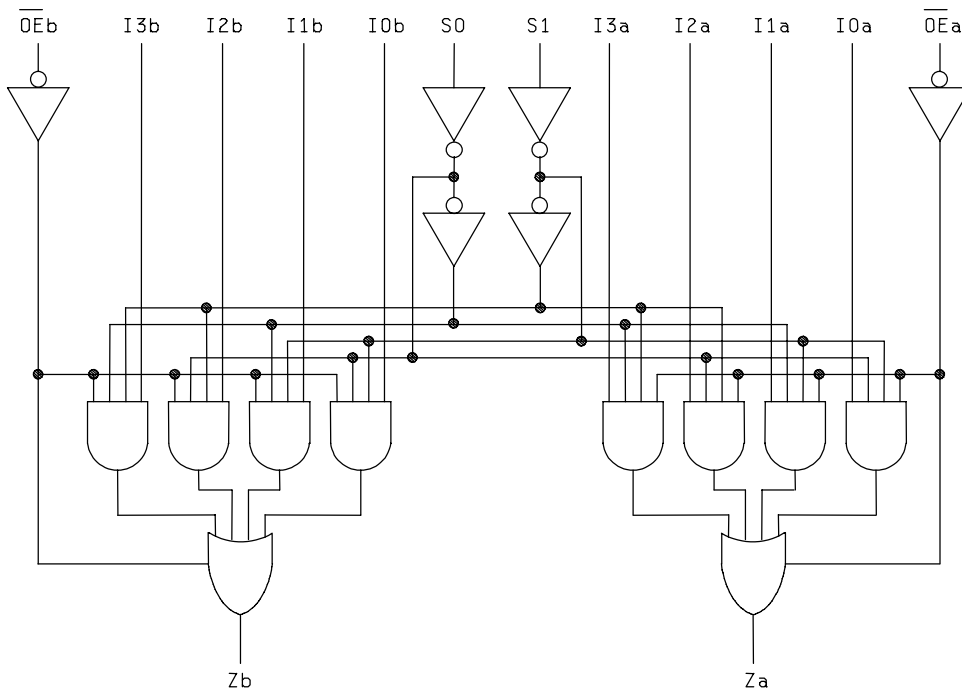
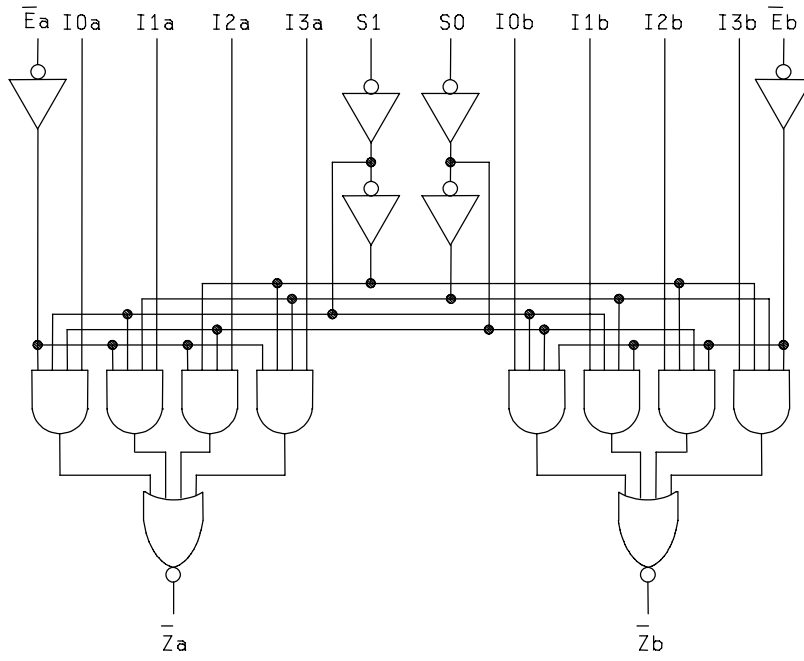


FIGURE 2. Logic diagrams - Continued.

DEVICE TYPE 09



DEVICE TYPE 10

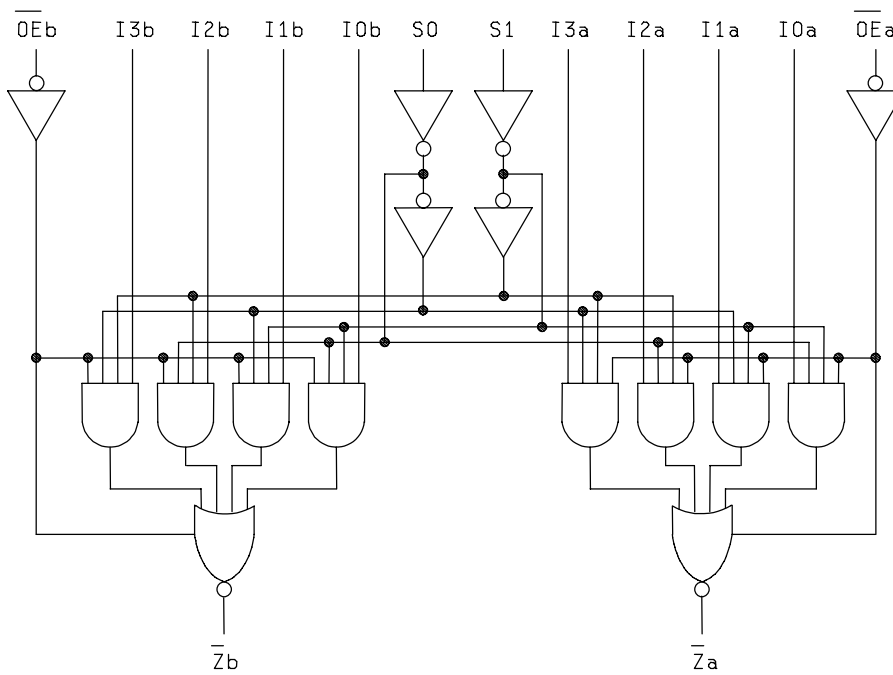


FIGURE 2. Logic diagrams - Continued.

Device type 01

INPUTS				OUTPUTS	
\bar{E}	S2	S1	S0	\bar{Z}	Z
H	X	X	X	H	L
L	L	L	L	$\bar{I}0$	I0
L	L	L	H	$\bar{I}1$	I1
L	L	H	L	$\bar{I}2$	I2
L	L	H	H	$\bar{I}3$	I3
L	H	L	L	$\bar{I}4$	I4
L	H	L	H	$\bar{I}5$	I5
L	H	H	L	$\bar{I}6$	I6
L	H	H	H	$\bar{I}7$	I7

Device type 02

SELECT INPUTS		INPUTS (a or b)					OUTPUT
S0	S1	\bar{E}	I0	I1	I2	I3	Z
X	X	H	X	X	X	X	L
L	L	L	L	X	X	X	L
L	L	L	H	X	X	X	H
H	L	L	X	L	X	X	L
H	L	L	X	H	X	X	H
L	H	L	X	X	L	X	L
L	H	L	X	X	H	X	H
H	H	L	X	X	X	L	L
H	H	L	X	X	X	H	H

H = HIGH voltage level
L = LOW voltage level
X = Immaterial

FIGURE 3. Truth tables.

Device type 03

INPUTS				OUTPUT
\bar{E}	S	I0	I1	Z
H	X	X	X	L
L	H	X	L	L
L	H	X	H	H
L	L	L	X	L
L	L	H	X	H

Device type 04

INPUTS				OUTPUT
\bar{E}	S	I0	I1	\bar{Z}
H	X	X	X	H
L	L	L	X	H
L	L	H	X	L
L	H	X	L	H
L	H	X	H	L

Device type 05

INPUTS				OUTPUTS	
\bar{OE}	S2	S1	S0	\bar{Z}	Z
H	X	X	X	Z	Z
L	L	L	L	$\bar{1}0$	10
L	L	L	H	$\bar{1}1$	11
L	L	H	L	$\bar{1}2$	12
L	L	H	H	$\bar{1}3$	13
L	H	L	L	$\bar{1}4$	14
L	H	L	H	$\bar{1}5$	15
L	H	H	L	$\bar{1}6$	16
L	H	H	H	$\bar{1}7$	17

Device type 06

OUTPUT ENABLE	SELECT INPUT	DATE INPUTS		OUTPUTS
\bar{OE}	S	I0	I1	Z
H	X	X	X	(Z)
L	H	X	L	L
L	H	X	H	H
L	L	L	X	L
L	L	H	X	H

H = HIGH voltage level
 L = LOW voltage level
 X = Immaterial
 (Z) = High impedance

FIGURE 3. Truth tables - Continued.

Device type 07

OUTPUT ENABLE	SELECT INPUT	DATE INPUTS		OUTPUTS
\overline{OE}	S	I 0	I 1	\overline{Z}
H	X	X	X	Z
L	H	X	L	H
L	H	X	H	L
L	L	L	X	H
L	L	H	X	L

Device type 08

SELECT INPUTS		DATA INPUTS				OUTPUT ENABLE	OUTPUT
S0	S1	I 0	I 1	I 2	I 3	\overline{OE}	Z
X	X	X	X	X	X	H	(Z)
L	L	L	X	X	X	L	L
L	L	H	X	X	X	L	H
H	L	X	L	X	X	L	L
H	L	X	H	X	X	L	H
L	H	X	X	L	X	L	L
L	H	X	X	H	X	L	H
H	H	X	X	X	L	L	L
H	H	X	X	X	H	L	H

H = HIGH voltage level
 L = LOW voltage level
 X = Immaterial
 (Z) = High impedance

FIGURE 3. Truth tables - Continued.

Device type 09

SELECT INPUTS		INPUTS (a or b)					OUTPUT
S0	S1	\bar{E}	I0	I1	I2	I3	\bar{Z}
X	X	H	X	X	X	X	H
L	L	L	L	X	X	X	H
L	L	L	H	X	X	X	L
H	L	L	X	L	X	X	H
H	L	L	X	H	X	X	L
L	H	L	X	X	L	X	H
L	H	L	X	X	H	X	L
H	H	L	X	X	X	L	H
H	H	L	X	X	X	H	L

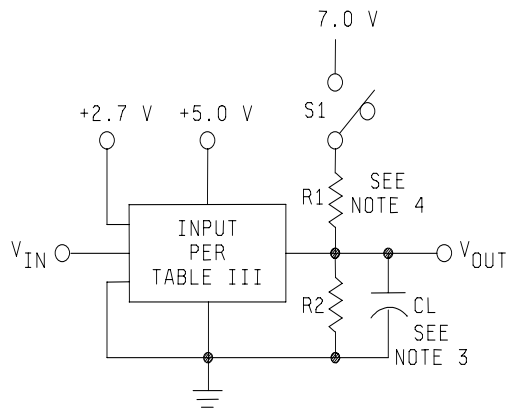
Device type 10

SELECT INPUTS		DATA INPUTS				OUTPUT ENABLE	OUTPUT
S0	S1	I0	I1	I2	I3	\bar{OE}	\bar{Z}
X	X	X	X	X	X	H	(Z)
L	L	L	X	X	X	L	H
L	L	H	X	X	X	L	L
H	L	X	L	X	X	L	H
H	L	X	H	X	X	L	L
L	H	X	X	L	X	L	H
L	H	X	X	H	X	L	L
H	H	X	X	X	L	L	H
H	H	X	X	X	H	L	L

Address inputs S0 and S1 are common to both sections

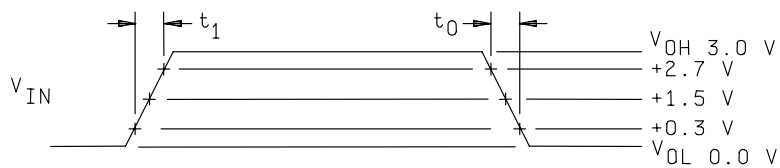
H = HIGH voltage level
 L = LOW voltage level
 X = Immaterial
 (Z) = High impedance

FIGURE 3. Truth tables - Continued.



Test Circuit

Test Type	S1
t_{PLH}	Open
t_{PHL}	Open
t_{PHZ}	Open
t_{PZH}	Open
t_{PLZ}	Closed
t_{PZL}	Closed

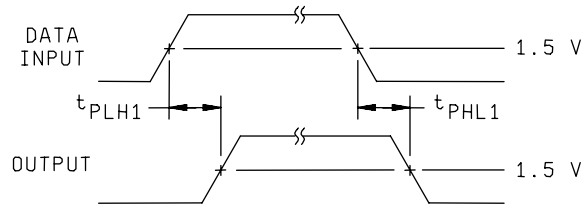


NOTES:

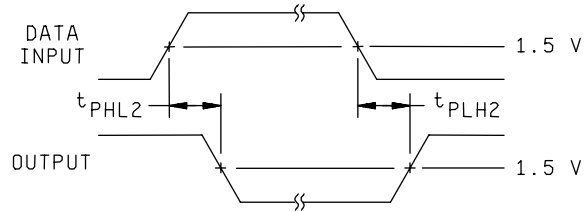
1. V_{IN} input pulse has the following characteristics: $t_1 = t_0 \leq 2.5$ ns, $PRR \leq 1$ MHz, $Z_{OUT} \approx 50\Omega$.
2. Inputs not under test are at ground.
3. $C_L = 50$ pF $\pm 10\%$ including scope probe, wiring and stray capacitance without package in test fixture.
4. $R_1 = R_2 = 499\Omega \pm 5\%$.
5. Voltage measurements are to be made with respect to network ground terminal.

FIGURE 4. Switching time test circuit and waveform for all device types.

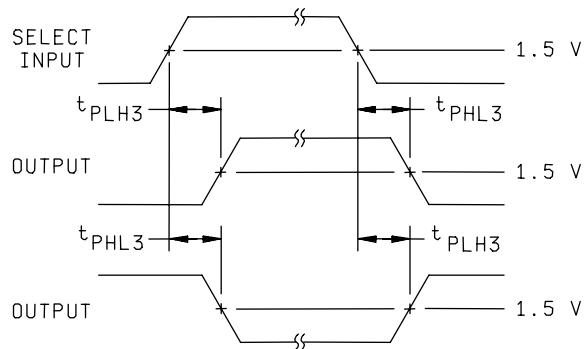
MIL-M-38510/339D



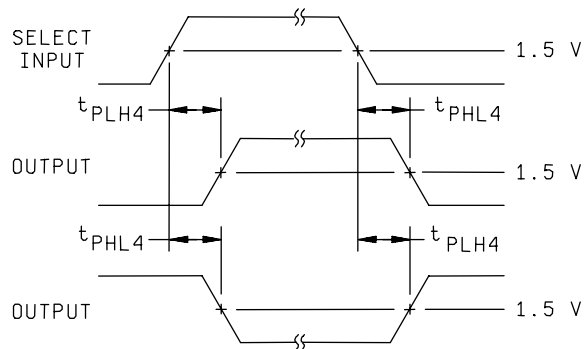
DEVICE TYPES 01,02,03,05,06 AND 08



DEVICE TYPES 01,04,05,07,09 AND 10



DEVICE TYPES 01,02,03,05,06 AND 08



DEVICE TYPES 01,04,05,07,09 AND 10

FIGURE 4. Switching time waveform - Continued.

MIL-M-38510/339D

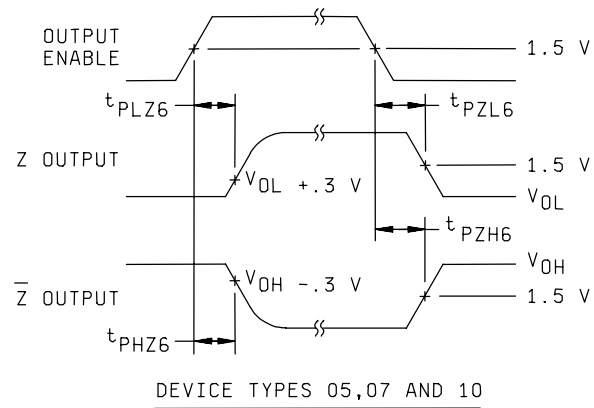
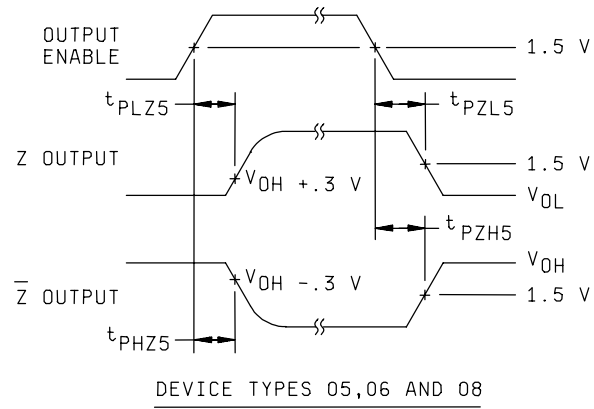
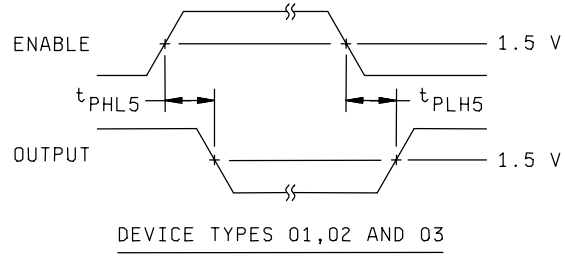
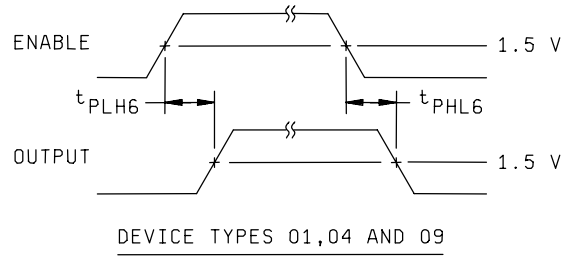


FIGURE 4. Switching time waveform - Continued.

TABLE III. Group A inspection for device type 01.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F Case 2 1/	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Limits		Unit						
																				Measured terminal	Min		Max					
1 $T_c = 25^\circ\text{C}$	V_{OL}	3007	Test no.	1																								
				2																								
				3																								
				4																								
				5																								
				6																								
				7																								
				8																								
				9																								
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See footnotes at end of table.

TABLE III. Group A inspection for device type 01 - Continued.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F	Terminal conditions																Limits		Unit							
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured terminal	Min		Max						
9	t_{PH4}	3003	139					Z	Z	OUT	0.0 V	E	0.0 V	GND	GND	0.0 V	S2	S1	S0	I7	I6	I5	I4			S0 to Z	4.0	9.0	ns
		Fig 4	140								0.0 V															S1 to Z	"	"	"
		"	141																							S2 to Z	"	"	"
	t_{PHL4}	"	142								2.7 V															S0 to Z	3.2	7.5	"
	"	"	143																							S1 to Z	"	"	"
	"	"	144																							S2 to Z	"	"	"
10	Same tests and terminal conditions as subgroup 9, except $T_c = +125^\circ\text{C}$ and for the following limits. $t_{PH1} = 2.5$ to 8.5 ns $t_{PH2} = 3.5$ to 9.0 ns $t_{PH3} = 4.5$ to 13.5 ns $t_{PH4} = 4.0$ to 9.5 ns $t_{PH5} = 4.0$ to 12.0 ns $t_{PH6} = 3.0$ to 8.0 ns $t_{PHL2} = 1.5$ to 6.0 ns $t_{PHL4} = 3.0$ to 8.0 ns $t_{PHL6} = 2.5$ to 6.5 ns																												
11	Same tests, terminal conditions and limits as for subgroup 10, except $T_c = -55^\circ\text{C}$.																												

1/ For case 2 pins not referenced are N/C.
2/ I_{IL} limits shall be as follows:

Test	Min/Max limits in mA for circuit		
	A	B	C
I_{IL}	-0.25/- .60	-0.03/- .60	- .03/- .60

3/ A = 2.5 V, B = 0.5 V, H ≥ 1.5 V, L ≤ 1.5 V.
4/ Perform function sequence at $V_{CC} = 4.5$ V and repeat at $V_{CC} = 5.5$ V.

TABLE III. Group A inspection for device type 02.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F 1/	Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).																Limits	Unit				
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16						
1	V_{OH}	3006	Case 2	E a	S1	I3a	I2a	I1a	I0a	Za	GND	Zb	I0b	I1b	I2b	I3b	S0	E b	Vcc	20	16	Min	Max		
Tc = 25°C			1	0.8 V	0.8 V			2.0 V	2.0 V	-1 mA	GND						0.8 V	0.8 V	4.5 V			2.5		V	
			2	"	0.8 V			2.0 V			GND														"
			3	"	2.0 V		2.0 V																		"
			4	"	2.0 V		2.0 V																		"
			5	"	0.8 V																				"
			6	"	0.8 V																				"
			7	"	2.0 V																				"
			8	"	2.0 V																				"
			9	2.0 V	0.8 V						20 mA														0.5
			10	0.8 V	0.8 V				0.8 V																"
			11	"	0.8 V																				"
			12	"	2.0 V		0.8 V																		"
			13	"	2.0 V		0.8 V																		"
			14	"	2.0 V		0.8 V				20 mA														"
			15	"	0.8 V																				"
			16	"	0.8 V																				"
			17	"	2.0 V																				"
			18																						"
			19	-18 mA																					-1.2
		20																						"	
		21																						"	
		22																						"	
		23																						"	
		24																						"	
		25																						"	
		26																						"	
		27																						"	
		28																						"	
		29																						"	
		30																						"	
		31	2.7 V																					20	
		32	2.7 V																					"	
		33	4.5 V	0.0 V	2.7 V																			"	
		34	"	0.0 V				2.7 V																"	
		35	"	4.5 V																				"	
		36	"	"				2.7 V																"	
		37	"	"																				"	
		38	"	"																				"	
		39	0.0 V	0.0 V																				"	
		40	0.0 V	0.0 V																				"	
		41																						"	
		42																						"	
		43	7.0 V																					100	
		44		7.0 V																				"	
		45	4.5 V	0.0 V	7.0 V																			"	
		46	"	0.0 V				7.0 V																"	
		47	"	4.5 V																				"	
		48	"	"					7.0 V															"	
		49	"	"																				"	
		50	0.0 V	0.0 V																				"	
		51	0.0 V	0.0 V																				"	
		52	0.0 V	0.0 V																				"	
		53																						"	
		54																						"	

See footnotes at end of table.

TABLE III. Group A inspection for device type 03.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F Case 2 1/	Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).																Limits		Unit	
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Min	Max		
1	V_{OL}	3007	S	0.8 V	0.8 V	2.0 V	2.0 V	20 mA	20 mA	11d	11d	12	12	13	13	14	14	15	15	16			
1 $T_c = 25^\circ C$		"	2	2.0 V	2.0 V	0.8 V	0.8 V	20 mA	20 mA									0.8 V	4.5 V	Za	0.5	V	
		"	3	0.8 V	2.0 V		2.0 V			2.0 V											Za		"
		"	4	2.0 V			0.8 V			0.8 V											Zb		"
		"	5	0.8 V			2.0 V			2.0 V											Zb		"
		"	6	2.0 V			0.8 V			0.8 V											Zd		"
		"	7	0.8 V			2.0 V			2.0 V											Zd		"
		"	8	2.0 V			0.8 V			0.8 V											Zc		"
		V_{OH}	3006	9	0.8 V	2.0 V	0.8 V	2.0 V	-1 mA										20 mA	2.0 V	Zc		"
		"	"	10	2.0 V	0.8 V	2.0 V	2.0 V	-1 mA										20 mA	0.8 V	Zc	2.5	"
		"	"	11	0.8 V			2.0 V	0.8 V	-1 mA											Za		"
		"	"	12	2.0 V			0.8 V	2.0 V	-1 mA											Zb		"
		"	"	13	0.8 V			2.0 V	2.0 V	-1 mA											Zb		"
		"	"	14	2.0 V			0.8 V	2.0 V	-1 mA											Zd		"
		"	"	15	0.8 V			2.0 V	2.0 V	-1 mA											Zd		"
		"	"	16	2.0 V			0.8 V	2.0 V	-1 mA											Zc		"
		V_{IC}		17	-18 mA																Zc		-1.2
			18				-18 mA													S			"
			19																	10a			"
			20																	11a			"
			21				-18 mA													10b			"
			22																	11b			"
			23																	11d			"
			24																	10c			"
			25																	11c			"
			26																	10c			"
			27	2.7 V																E			"
	I_{IH1}	3010	28	4.5 V																S		20	μA
		"	29	0.0 V			2.7 V													10a			"
		"	30	4.5 V																11a			"
		"	31	0.0 V																10b			"
		"	32	0.0 V																11b			"
		"	33	4.5 V																11d			"
		"	34	0.0 V																10c			"
		"	35	4.5 V																11c			"
		"	36																	10c			"
		"	37	7.0 V																E			"
	I_{IH2}	"	38	4.5 V																S		100	"
		"	39	0.0 V			7.0 V													10a			"
		"	40	4.5 V																11a			"
		"	41	0.0 V																10b			"
		"	42	0.0 V																11b			"
		"	43	4.5 V																11d			"
		"	44	0.0 V																10c			"
		"	45	4.5 V																11c			"
		"	46																	10c			"
		"																		E			"

See footnotes at end of table.

TABLE III. Group A inspection for device type 03.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F Case 2 1/ Test no.	Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).																Limits		Unit			
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured terminal	Min		Max		
1 Tc = 25°C	I _{IL1}	3009	47	0.5V														S	2/	2/	mA				
			48	0.0V	0.5V														I0a	"	"	"			
			49	4.5V		0.5V														I1a	"	"	"		
			50	0.0V			0.5V													I0b	"	"	"		
			51	4.5V				0.5V												I1b	"	"	"		
			52	4.5V					0.5V											I1d	"	"	"		
			53	0.0V						0.5V										I0d	"	"	"		
			54	4.5V											0.5V					I1c	"	"	"		
			55	0.0V																I0c	"	"	"		
			56																	E	"	"	"		
2	I _{OS}	3011	57	0.0V	4.5V	0.0V												E	0.5V	-60	-150				
			58	"		4.5V	0.0V											Za	"	"	"				
			59	"				0.0V										Zb	"	"	"				
			60	"														Zd	"	"	"				
3	I _{OP}		61				2.5V											Za	5.5V	4.5V	60.5/				
			62						2.5V									Zb	"	"	"				
			63							2.5V								Zc	"	"	"				
			64									4.5V	4.5V					Zc	"	"	"				
4	I _{CC}	3005	65	4.5V	4.5V	4.5V	4.5V	4.5V									V _{CC}	4.5V	4.5V	23	"				
3	Same tests, terminal conditions, and limits as subgroup 1, except Tc = +125°C and V _{IC} tests are omitted.																								
7	Same tests, terminal conditions, and limits as subgroup 1, except Tc = 55°C and V _{IC} tests are omitted.																								
7 Tc = 25°C	Functional test 3/	3014	66	A	A	A	L	L	GND	L	A	A	L	A	A	L	A	A	A	A	A	A	4/		
			67	B	"	A	L	"	A	L	"	L	A	"	L	A	"	L	A	"	L	A	"	"	
			68	B	"	B	H	"	B	H	"	H	B	"	H	B	"	H	B	"	H	B	"	"	
			69	A	"	B	L	"	B	L	"	L	B	"	L	B	"	L	B	"	L	B	"	"	
			70	B	"	A	L	"	A	L	"	L	A	"	L	A	"	L	A	"	L	A	"	"	
			71	A	"	B	A	"	B	A	"	H	A	"	H	A	"	H	A	"	H	A	"	"	
			72	0.0V	IN	OUT																			
			73	2.7V	IN	OUT																			
			74	0.0V			IN	IN	OUT	OUT															
			75	2.7V				IN	OUT	OUT															
			76	2.7V																					
77	0.0V																								
78	2.7V																								
79	0.0V																								
80	0.0V	IN	OUT																						
81	2.7V		IN	OUT																					
82	0.0V				IN	IN	OUT	OUT																	
83	2.7V																								
84	2.7V																								
85	0.0V																								
86	2.7V																								
87	0.0V																								
88	2.7V																								
89	"																								
90	"																								
91	"																								

See footnotes at end of table.

TABLE III. Group A inspection for device type 03.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F Case 2 1/ Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured terminal	Limits		Unit		
				Case 2 1/ Test no.	10a	11a	Za	10b	11b	Zb	GND	Zd	11d	10d	Zc	11c	10c	19	20		Min	Max			
9 $T_c = 25^\circ\text{C}$	t_{PHL5}	3003 Fig. 4	92	0.0 V	2.7 V		OUT											IN	5.0 V	E to Za	2.5	6.5	ns		
			93	"	"											2.7 V			"	"	E to Zb	"	"	"	
			94	"	"									OUT						"	"	E to Zd	"	"	"
			95	"	"											2.7 V	OUT			"	"	E to Zc	"	"	"
			96	IN	2.7 V	0.0 V	OUT													0.0 V	"	S to Za	4.0	10.0	"
			97	"	"					2.7 V	0.0 V	OUT								"	"	S to Zb	"	"	"
			98	"	"											0.0 V	2.7 V			"	"	S to Zd	"	"	"
			99	"	"															"	"	S to Zc	"	"	"
			100	"	0.0 V	2.7 V	OUT										OUT	0.0 V	2.7 V		"	S to Zc	"	"	"
			101	"	"						0.0 V	2.7 V	OUT							"	"	S to Za	3.0	7.0	"
			102	"	"											2.7 V	0.0 V			"	"	S to Zb	"	"	"
			103	"	"												OUT	2.7 V	0.0 V		"	S to Zd	"	"	"
			10	Same tests and terminal conditions as subgroup 9, except $T_c = +125^\circ\text{C}$ and use limits from table I.																					
11	Same tests, terminal conditions and limits as for subgroup 10, except $T_c = -55^\circ\text{C}$.																								

1/ For case 2 pins not referenced are N/C.
2/ I_{IL} limits shall be as follows:

Test	Min/Max limits in mA for circuit			
	A	B	C	D
I_{IL}	-0.25/-0.60	-0.03/-0.60	-0.03/-0.60	0.0/-0.30

3/ A = 2.5 V, B = 0.5 V, H ≥ 1.5 V, L ≤ 1.5 V.
4/ Perform function sequence at $V_{cc} = 4.5$ V and repeat at $V_{cc} = 5.5$ V.
5/ I_{lo} minimum limit for circuit D shall be 35 mA.

TABLE III. Group A inspection for device type 04.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F, Case 2 $\frac{1}{1}$	Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).																Measured terminal	Limits		Unit	
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		Min	Max		
1	I_{L1}	3009	47	0.5 V														S	2/	2/	mA			
			48	0.0 V	0.5 V														10a	"	"	"		
			49	4.5 V		0.5 V													11a	"	"	"		
			50	0.0 V				0.5 V											10b	"	"	"		
			51	4.5 V															11b	"	"	"		
			52	4.5 V							0.5 V								11d	"	"	"		
			53	0.0 V								0.5 V							10d	"	"	"		
			54	4.5 V									0.5 V						11c	"	"	"		
			55	0.0 V															10c	"	"	"		
			56										0.0 V							E	"	"	"	
2	I_{OS}	3011	57	0.0 V	0.0 V	4.5 V	0.0 V											Z a	-60	-150	"			
			58	"				0.0 V	4.5 V	0.0 V								Z b	"	"	"			
			59	"						0.0 V	4.5 V	0.0 V						Z d	"	"	"			
			60	"									0.0 V	4.5 V	0.0 V			Z c	"	"	"			
7	Functional test $\frac{3}{3}$	3014	61	"	5.5 V		2.5 V											Z a	60		"			
			62	"					2.5 V									Z b	"	"	"			
			63	"						2.5 V								Z d	"	"	"			
			64	"														Z c	"	"	"			
8	t_{PUH2}	3003	65	4.5 V	4.5 V	4.5 V	4.5 V			4.5 V	4.5 V							V_{CC}	"	15	"			
			66	A	A	A	H	A	A	H	A	A	A	H	A	A	A	A	A	A	A	4/	All outputs	
			67	B	"	"	H	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			68	B	"	"	L	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			69	A	"	"	B	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			70	B	"	"	H	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			71	A	"	"	L	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			72	0.0 V	IN		OUT														0.0 V	2.5	5.9	ns
			73	2.7 V		IN	OUT														"	"	"	"
			74	0.0 V				IN				OUT									"	"	"	"
75	2.7 V					IN			OUT									"	"	"	"			
76	2.7 V									OUT								"	"	"	"			
77	0.0 V										IN							"	"	"	"			
78	2.7 V											IN						"	"	"	"			
79	0.0 V												IN					"	"	"	"			

See footnotes at end of table.

TABLE III. Group A inspection for device type 04.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F Case 2 $\frac{1}{1}$ Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Limits	Unit					
				Measured terminal	Min	Max																				
9 $T_c = 25^\circ\text{C}$	t_{PHL2}	3003 Fig. 4	80	0.0 V	IN	10a	11a	$\bar{Z}a$	10b	11b	$\bar{Z}b$	GND	10	12	$\bar{Z}d$	11d	11d	10c	19	0.0 V	1.5	4.0	ns			
			81	2.7 V				OUT																		
			82	0.0 V							IN															
			83	2.7 V								OUT														
			84	2.7 V										OUT	IN											
			85	0.0 V										OUT		IN										
			86	2.7 V													OUT	IN								
			87	0.0 V													OUT		IN							
			88	2.7 V																						
			89	"																						
			90	"																						
			91	"																						
			10	t_{PHL6}	"	92	0.0 V																			
93	"																									
94	"																									
95	"																									
96	IN	0.0 V				2.7 V	OUT																			
11	t_{PHL4}	"	97	"																						
			98	"																						
			99	"																						
			100	"	2.7 V	0.0 V	OUT																			
			101	"																						
10	Same tests and terminal conditions as subgroup 9, except $T_c = +125^\circ\text{C}$ and use limits from table I.	"	102	"																						
			103	"																						
			103	"																						

1/ For case 2 pins not referenced are N/C.
2/ I_{IL} limits shall be as follows:

Test	Min/Max limits in mA for circuit			
	A	B	C	D
I_{IL}	-25/-60	-03/-60	-03/-60	0.0/-0.30

3/ A = 2.5 V minimum, B = 0.5 V. $H \geq 1.5$ V, $L \leq 1.5$ V.
4/ Perform function sequence at $V_{CC} = 4.5$ V and repeat at $V_{CC} = 5.5$ V.

TABLE III. Group A inspection for device type 05.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F 1/1	Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).																Measured terminal	Limits		Unit																		
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		Min	Max																			
1	V_{OL}	3007	1	13	2.0V	Z	20 mA	Z	20 mA	0.8V	S1	0.8V	S2	0.8V	GND	GND	S0	0.8V	17	16	15	14	15	19	20	4.5V	Z	0.5	V												
			2			2.0V							0.8V					2.0V																							
			3			2.0V							0.8V					2.0V																							
			4			2.0V							0.8V					2.0V																							
			5										0.8V					2.0V																							
			6										0.8V					2.0V																							
			7										0.8V					2.0V																							
			8										0.8V					2.0V																							
			9										0.8V					2.0V																							
			10										0.8V					2.0V																							
			1	V_{OH}	3006	11																																			
12																																									
13																																									
14																																									
15																																									
16																																									
17																																									
18																																									
19																																									
20																																									
1	V_{IC}					21																																			
			22																																						
			23																																						
			24																																						
			25																																						
			26																																						
			27																																						
			28																																						
			29																																						
			30																																						
			1	I_{IH1}	3010	31																																			
32																																									
33																																									
34																																									
35																																									
36																																									
37																																									
38																																									
39																																									
40																																									
1	I_{IH2}					41																																			
			42																																						
			43																																						
			44																																						
			45																																						
			46																																						
			47																																						
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54																																									

See footnotes at end of table.

TABLE III. Group A inspection for device type 05.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F 1/ <u>1</u> / Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Limits	Unit	
				2	3	4	5	7	8	9	10	12	13	14	15	16	Measured terminal	Min	Max			
9	t_{PZH5}	3003	137				10	Z	Z	OE	GND	S2	S1	S0	17	16	15	14	20		ns	
	t_{PZH6}	Fig. 4	138				5	OUT	OUT	IN	GND	0.0 V	0.0 V	0.0 V					5.0 V	\overline{QE} to Z	3.5	7.0
	t_{PZL5}	"	139				4	OUT	OUT	OUT	"	"	"	"	"	"	"	"	"	\overline{QE} to \overline{Z}	2.5	6.0
	t_{PZL6}	"	140				4	OUT	OUT	OUT	"	"	"	"	"	"	"	"	"	\overline{QE} to Z	3.5	7.5
	t_{PHZ5}	"	141				4	OUT	OUT	OUT	"	"	"	"	"	"	"	"	"	\overline{QE} to \overline{Z}	2.5	6.0
	t_{PHZ6}	"	142				4	OUT	OUT	OUT	"	"	"	"	"	"	"	"	"	\overline{QE} to Z	2.0	5.5
10	t_{PLZ5}	"	143				4	OUT	OUT	OUT	"	"	"	"	"	"	"	"	"	\overline{QE} to \overline{Z}	2.5	5.5
	t_{PLZ6}	"	144				4	OUT	OUT	OUT	"	"	"	"	"	"	"	"	"	\overline{QE} to Z	1.0	4.5
11	Same tests and terminal conditions as subgroup 9, except $T_C = +125^\circ\text{C}$ and for the following limits. $t_{PH1} = 2.5$ to 9.0 ns $t_{PH3} = 3.5$ to 14.0 ns $t_{PH4} = 2.5$ to 8.5 ns $t_{PH2} = 2.5$ to 11.5 ns $t_{PH4} = 3.5$ to 11.5 ns $t_{PH3} = 3.0$ to 10.5 ns $t_{PH1} = 1.0$ to 6.0 ns $t_{PH2} = 1.0$ to 6.0 ns $t_{PH4} = 3.2$ to 8.0 ns $t_{PZH5} = 2.0$ to 5.5 ns $t_{PZH6} = 2.0$ to 6.0 ns $t_{PZL5} = 1.0$ to 5.5 ns $t_{PZL6} = 1.0$ to 5.0 ns																					
11	Same tests, terminal conditions and limits as for subgroup 10, except $T_C = -55^\circ\text{C}$.																					

Test	Min/Max limits in mA for circuit		
	A	B	C
I_{IL}	-0.25/- .60	-0.03/- .60	-0.03/- .60

1/ For case 2 pins not referenced are N/C.
 2/ I_{IL} limits shall be as follows:

3/ A = 2.5 V, B = 0.5 V, H ≥ 1.5 V, L ≤ 1.5 V.
 4/ Perform function sequence at $V_{CC} = 4.5$ V and repeat at $V_{CC} = 5.5$ V.

TABLE III. Group A inspection for device type 06.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F	Cases 1-16																Measured terminal	Limits		Unit	
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		Min	Max		
1 Tc = 25°C	I _{IL1}	3009	Case 2	S	10a	11a	Za	10b	11b	Zb	GND	Zd	11d	11c	10c	OE	V _{CC}	S	2/	mA				
			Test no.	47	0.5 V														5.5 V	10a	"	"		
				48	0.0 V	0.5 V														"	11a	"	"	
				49	4.5 V		0.5 V													"	10b	"	"	
				50	0.0 V			0.5 V												"	11b	"	"	
				51	4.5 V															"	11d	"	"	
				52	4.5 V										0.5 V					"	10d	"	"	
				53	0.0 V											0.5 V				"	11c	"	"	
				54	4.5 V												0.5 V			"	10c	"	"	
				55	0.0 V													0.5 V		"	OE	"	"	
				56																"		"	"	
				57	0.0 V	4.5 V		0.0 V												"	Za	-60	-150	
				58	"	"				4.5 V			0.0 V							"	Zb	"	"	
				59	"	"								0.0 V						"	Zd	"	"	
				60	"	"									4.5 V					"	Zc	"	"	
				61	0.0 V	0.0 V				2.5 V			2.5 V							"	Za	35	"	
	62																"	Zb	"	"				
	63						0.0 V			2.5 V							"	Zd	"	"				
	64											0.0 V					"	Zc	"	"				
	65	4.5 V	4.5 V	4.5 V	2.7 V								2.5 V		0.0 V		"	Za	"	"				
	66	"	"														"	Zb	"	"				
	67	"	"							2.7 V	4.5 V						"	Zd	"	"				
	68	"	"														"	Zc	"	"				
	69	0.0 V	0.0 V	4.5 V	0.5 V												"	Za	-50	"				
	70	"	"					0.0 V		0.5 V							"	Zb	"	"				
	71	"	"								0.5 V	4.5 V					"	Zd	"	"				
	72	"	"														"	Zc	"	"				
	73	4.5 V	0.0 V	4.5 V									0.5 V		0.0 V		"	Za	"	"				
	74	0.0 V	0.0 V	0.0 V	0.0 V							4.5 V	0.0 V		0.0 V		"	V _{CC}	15	mA				
	75	0.0 V	0.0 V	0.0 V	0.0 V							0.0 V	0.0 V		0.0 V		"	V _{CC}	22	"				
	76	A	A	B	L	A	A	B	B	L	GND	L	B	A	B		"			23	"			
2	Same tests, terminal conditions, and limits as subgroup 1, except T _c = +125°C and V _{IC} tests are omitted.																							
3	Same tests, terminal conditions, and limits as subgroup 1, except T _c = -55°C and V _{IC} tests are omitted.																							
7	Functional test 3/	3014	Case 2	A	B	L	A	B	B	L	GND	L	B	A	B	A	B	4/	All outputs					
Test no.			76	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V		
			77	"	B	B	L	A	B	B	B	L	"	L	B	B	B	B	"	"	"	"	"	
			78	"	B	A	H	A	B	A	A	H	"	H	A	A	A	A	"	"	"	"	"	
			79	"	A	A	H	A	A	A	A	H	"	H	A	A	A	A	"	"	"	"	"	
			80	B	B	A	L	B	A	A	A	L	"	L	A	B	B	B	"	"	"	"	"	
			81	"	B	B	L	B	B	B	B	L	"	L	B	B	B	B	"	"	"	"	"	
			82	"	A	B	H	A	B	B	B	H	"	H	B	B	B	B	"	"	"	"	"	
			83	"	A	A	H	A	A	A	A	H	"	H	A	A	A	A	"	"	"	"	"	
8			Same tests, terminal conditions, and limits as for subgroup 7, except T _c = +125°C and T _c = -55°C.																					
9			t _{PHH}	3003	Case 2	IN	IN	OUT	OUT	OUT	OUT	OUT	GND	OUT	OUT	OUT	OUT	OUT	OUT	0.0 V	5.0 V	2.5	5.5	
Test no.					84	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V
					85	2.7 V	IN	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	0.0 V	5.0 V	2.5	5.5
					86	0.0 V	IN	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	0.0 V	5.0 V	2.5	5.5
					87	2.7 V	IN	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	0.0 V	5.0 V	2.5	5.5
					88	2.7 V	IN	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	0.0 V	5.0 V	2.5	5.5
	89	0.0 V			IN	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	0.0 V	5.0 V	2.5	5.5		
	90	2.7 V			IN	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	0.0 V	5.0 V	2.5	5.5		
	91	0.0 V			IN	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	0.0 V	5.0 V	2.5	5.5		

See footnotes at end of table.

TABLE III. Group A inspection for device type 06.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F, Case 2 $\frac{1}{1}$	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured terminal	Limits		Unit			
																					Min	Max				
9 $T_c = 25^\circ C$	t_{PH1}	3003 Fig. 4	Case 2 $\frac{1}{1}$	S	10a	11a	Za	10b	11b	Zb	GND	Zd	11d	10d	Zc	11c	10c	OE	5.0 V	10a to Za 11a to Zb	2.0	5.5	ns			
				92	0.0 V	IN	OUT	OUT													0.0 V					
				93	2.7 V	IN	OUT																11a to Za			
				94	0.0 V						IN	OUT											10b to Zb			
				95	2.7 V						IN	OUT											11b to Zb			
				96	2.7 V								OUT										11d to Zd			
				97	0.0 V									OUT		IN							10d to Zd			
				98	2.7 V																		11c to Zc			
				99	0.0 V																		10c to Zc			
				100	IN	0.0 V	2.7 V	OUT				0.0 V	2.7 V	OUT			2.7 V	0.0 V					S to Za	4.0	9.5	"
				101																			S to Zb			
				102																			S to Zc			
				103																			S to Za			
104																			S to Zc							
105																			S to Za	2.5	7.0	"				
106																			S to Zb							
107																			S to Zc							
108																			S to Za							
109																			S to Zb							
110																			S to Zc							
111																			S to Za							
112																			S to Zb							
113																			S to Zc							
114																			S to Za	2.0	6.0	"				
115																			S to Zb							
116																			S to Zc							
117																			S to Za							
118																			S to Zb							
119																			S to Zc							
120																			S to Za							
121																			S to Zb							
122																			S to Zc							
123																			S to Za							
10	Same tests and terminal conditions as subgroup 9, except $T_c = +125^\circ C$ and use limits from table I.																									
11	Same tests, terminal conditions and limits as for subgroup 10, except $T_c = -55^\circ C$.																									

1/ For case 2 pins not referenced are N/C.
2/ I_{IL} limits shall be as follows:

Test	Min/Max limits in mA for circuit			
	A	B	C	D
I_{IL}	-25/-60	-03/-60	-03/-60	0.0/-0.30

3/ A = 2.5 V, B = 0.5 V, H ≥ 1.5 V, L ≤ 1.5 V.
4/ Perform function sequence at $V_{CC} = 4.5$ V and repeat at $V_{CC} = 5.5$ V.

TABLE III. Group A inspection for device type 07.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F, 1/	Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).																Limits	Unit			
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16					
1	V_{OL}	3007	Case 2	S	10a	11a	12a	13	14	15	16	17	18	19	20	Measured terminal	Min	Max	V					
			Test no.	1	0.8V	2.0V	0.8V	2.0V	20mA	20mA													0.5	
			2	2.0V	0.8V																			
			3	0.8V																				
			4	2.0V																				
			5	0.8V																				
			6	2.0V																				
			7	0.8V																				
			8	2.0V																				
			9	0.8V																				
			10	2.0V																				
			11	0.8V																				
			12	2.0V																				
			13	0.8V																				
			14	2.0V																				
			15	0.8V																				
16	2.0V																							
2	V_{OH}	3006	17	-18mA																				
			18																					
			19																					
			20																					
			21																					
			22																					
			23																					
			24																					
			25																					
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See footnotes at end of table.

TABLE III. Group A inspection for device type 07.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F Case 2 1/	Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).																Limits	Unit					
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16							
1 Tc = 25°C	I _{IL1}	3009	47	0.5 V														S	2/	2/	mA					
			48	0.0 V	0.5 V														10a	"	"	"	"			
			49	4.5 V		0.5 V														11a	"	"	"	"		
			50	0.0 V				0.5 V												10b	"	"	"	"		
			51	4.5 V					0.5 V											11b	"	"	"	"		
			52	4.5 V								0.5 V								11d	"	"	"	"		
			53	0.0 V									0.5 V							10d	"	"	"	"		
			54	4.5 V										0.5 V						11c	"	"	"	"		
			55	0.0 V											0.5 V					10c	"	"	"	"		
			56																	OE	"	"	"	"		
			57	0.0 V	0.0 V	4.5 V	0.0 V														OE	"	"	"	"	
			58	"	"			0.0 V	4.5 V	0.0 V											Z a	-60	-150	"	"	
			59	"	"						0.0 V										Z b	"	"	"	"	
			60	"	"								4.5 V	0.0 V							Z d	"	"	"	"	
			61	"	5.5 V				2.5 V						0.0 V	4.5 V	0.0 V				Z c	"	"	"	"	
			62	"																	Z a	35	"	"	"	
63	"					2.5 V												Z b	"	"	"	"				
64	"										2.5 V			5.5 V				Z d	"	"	"	"				
65	"	4.5 V	4.5 V	2.7 V														Z c	"	"	"	"				
66	"				4.5 V	4.5 V	2.7 V											Z a	50	"	"	"				
67	"									2.7 V	4.5 V	4.5 V						Z b	"	"	"	"				
68	"												2.7 V	4.5 V	4.5 V			Z d	"	"	"	"				
69	4.5 V	4.5 V	0.0 V	0.5 V														Z c	"	"	"	"				
70	"				4.5 V	0.0 V	0.5 V											Z a	"	"	"	"				
71	"									0.5 V	0.0 V	4.5 V						Z b	"	"	"	"				
72	"																	Z d	"	"	"	"				
73	0.0 V	0.0 V	0.0 V								0.0 V	0.0 V						Z c	"	"	"	"				
74	4.5 V	0.0 V	4.5 V								4.5 V	0.0 V						V _{CC}	9.5	"	"	mA				
75	0.0 V	0.0 V	0.0 V								0.0 V	0.0 V						V _{CC}	23	"	"	"				
2	Same tests, terminal conditions, and limits as subgroup 1, except T _C = +125°C and V _{IC} tests are omitted.																									
3	Same tests, terminal conditions, and limits as subgroup 1, except T _C = -55°C and V _{IC} tests are omitted.																									
7 Tc = 25°C	Functional test 3/	3014	76	B	A	B	L	L	GND	L	B	A	A	L	B	A	L	L	B	A	A	B	4/			
			77	"	A	A	L	L	"	"	"	L	A	A	A	A	A	A	L	A	A	A	"	"		
			78	"	B	A	H	B	A	H	"	H	A	B	B	H	A	B	H	A	A	B	"	"	"	
			79	"	B	B	"	B	B	"	"	"	B	B	B	B	B	B	B	B	B	B	B	"	"	"
			80	"	A	A	B	"	A	B	"	"	A	A	A	"	A	A	"	"	A	A	"	"	"	"
			81	"	B	B	"	B	B	"	"	"	B	B	B	B	B	B	B	B	B	B	B	"	"	"
			82	"	B	B	"	B	B	"	"	"	B	B	B	B	B	B	B	B	B	B	B	"	"	"
			83	"	A	A	L	L	A	L	"	L	A	A	A	L	A	A	L	L	A	A	A	"	"	"
			8	Same tests, terminal conditions, and limits as for subgroup 7, except T _C = +125°C and T _C = -55°C.																						

See footnotes at end of table.

TABLE III. Group A inspection for device type 07.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F, Case 2 \sqrt{I}	Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).																Limits	Unit
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		
9	t_{PLH2}	3003 Fig. 4	S	10a	11a	$\bar{Z}a$	11b	10b	11b	11d	10d	$\bar{Z}c$	11c	10c	OE	19	20	Min	Max		
			84	0.0 V	IN	OUT	OUT								0.0 V		5.0 V	2.5	5.3	ns	
			85	2.7 V		IN	OUT													"	
			86	0.0 V				IN	OUT											"	
			87	2.7 V					OUT											"	
			88	2.7 V						IN										"	
			89	0.0 V							IN									"	
			90	2.7 V								OUT								"	
			91	0.0 V									IN							"	
			92	0.0 V	IN	OUT														"	
	t_{PH2}		93	2.7 V		IN	OUT													"	
			94	0.0 V				IN	OUT											"	
			95	2.7 V																"	
			96	2.7 V						IN										"	
			97	0.0 V							IN									"	
			98	2.7 V								OUT								"	
			99	0.0 V									IN							"	
			100	IN	2.7 V	0.0 V	OUT							IN						"	
	t_{PLH4}		101	"				2.7 V	0.0 V											"	
			102	"						0.0 V	2.7 V									"	
			103	"								OUT	0.0 V	2.7 V						"	
	t_{PH4}		104	"	0.0 V	2.7 V	OUT													"	
			105	"				0.0 V	2.7 V											"	
			106	"						2.7 V	0.0 V									"	
			107	"								OUT	2.7 V	0.0 V						"	
	t_{PH6}		108	0.0 V	0.0 V		OUT													"	
			109	"				0.0 V												"	
			110	"							0.0 V									"	
			111	"								OUT		0.0 V						"	
	t_{ZL6}		112	2.7 V		2.7 V	OUT													"	
			113	"					2.7 V											"	
			114	"						2.7 V										"	
			115	"								OUT	2.7 V							"	

See footnotes at end of table.

TABLE III. Group A inspection for device type 0Z.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F Case 2 1/	Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open)																Limits	Unit																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																												
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																														
9 $T_c = 25^\circ\text{C}$	t_{PHZ6}	3003 Fig. 4	Test no. S	10a	11a	11b	11c	11d	11e	11f	11g	11h	11i	11j	11k	11l	11m	11n	11o	11p	11q	11r	11s	11t	11u	11v	11w	11x	11y	11z	11aa	11ab	11ac	11ad	11ae	11af	11ag	11ah	11ai	11aj	11ak	11al	11am	11an	11ao	11ap	11aq	11ar	11as	11at	11au	11av	11aw	11ax	11ay	11az	11ba	11bb	11bc	11bd	11be	11bf	11bg	11bh	11bi	11bj	11bk	11bl	11bm	11bn	11bo	11bp	11bq	11br	11bs	11bt	11bu	11bv	11bw	11bx	11by	11bz	11ca	11cb	11cc	11cd	11ce	11cf	11cg	11ch	11ci	11cj	11ck	11cl	11cm	11cn	11co	11cp	11cq	11cr	11cs	11ct	11cu	11cv	11cw	11cx	11cy	11cz	11da	11db	11dc	11dd	11de	11df	11dg	11dh	11di	11dj	11dk	11dl	11dm	11dn	11do	11dp	11dq	11dr	11ds	11dt	11du	11dv	11dw	11dx	11dy	11dz	11ea	11eb	11ec	11ed	11ee	11ef	11eg	11eh	11ei	11ej	11ek	11el	11em	11en	11eo	11ep	11eq	11er	11es	11et	11eu	11ev	11ew	11ex	11ey	11ez	11fa	11fb	11fc	11fd	11fe	11ff	11fg	11fh	11fi	11fj	11fk	11fl	11fm	11fn	11fo	11fp	11fq	11fr	11fs	11ft	11fu	11fv	11fw	11fx	11fy	11fz	11ga	11gb	11gc	11gd	11ge	11gf	11gg	11gh	11gi	11gj	11gk	11gl	11gm	11gn	11go	11gp	11gq	11gr	11gs	11gt	11gu	11gv	11gw	11gx	11gy	11gz	11ha	11hb	11hc	11hd	11he	11hf	11hg	11hh	11hi	11hj	11hk	11hl	11hm	11hn	11ho	11hp	11hq	11hr	11hs	11ht	11hu	11hv	11hw	11hx	11hy	11hz	11ia	11ib	11ic	11id	11ie	11if	11ig	11ih	11ii	11ij	11ik	11il	11im	11in	11io	11ip	11iq	11ir	11is	11it	11iu	11iv	11iw	11ix	11iy	11iz	11ja	11jb	11jc	11jd	11je	11jf	11jg	11jh	11ji	11jj	11jk	11jl	11jm	11jn	11jo	11jp	11jq	11jr	11js	11jt	11ju	11jv	11jw	11jx	11jy	11jz	11ka	11kb	11kc	11kd	11ke	11kf	11kg	11kh	11ki	11kj	11kk	11kl	11km	11kn	11ko	11kp	11kq	11kr	11ks	11kt	11ku	11kv	11kw	11kx	11ky	11kz	11la	11lb	11lc	11ld	11le	11lf	11lg	11lh	11li	11lj	11lk	11ll	11lm	11ln	11lo	11lp	11lq	11lr	11ls	11lt	11lu	11lv	11lw	11lx	11ly	11lz	11ma	11mb	11mc	11md	11me	11mf	11mg	11mh	11mi	11mj	11mk	11ml	11mn	11mo	11mp	11mq	11mr	11ms	11mt	11mu	11mv	11mw	11mx	11my	11mz	11na	11nb	11nc	11nd	11ne	11nf	11ng	11nh	11ni	11nj	11nk	11nl	11nm	11nn	11no	11np	11nq	11nr	11ns	11nt	11nu	11nv	11nw	11nx	11ny	11nz	11oa	11ob	11oc	11od	11oe	11of	11og	11oh	11oi	11oj	11ok	11ol	11om	11on	11oo	11op	11oq	11or	11os	11ot	11ou	11ov	11ow	11ox	11oy	11oz	11pa	11pb	11pc	11pd	11pe	11pf	11pg	11ph	11pi	11pj	11pk	11pl	11pm	11pn	11po	11pp	11pq	11pr	11ps	11pt	11pu	11pv	11pw	11px	11py	11pz	11qa	11qb	11qc	11qd	11qe	11qf	11qg	11qh	11qi	11qj	11qk	11ql	11qm	11qn	11qo	11qp	11qq	11qr	11qs	11qt	11qu	11qv	11qw	11qx	11qy	11qz	11ra	11rb	11rc	11rd	11re	11rf	11rg	11rh	11ri	11rj	11rk	11rl	11rm	11rn	11ro	11rp	11rq	11rr	11rs	11rt	11ru	11rv	11rw	11rx	11ry	11rz	11sa	11sb	11sc	11sd	11se	11sf	11sg	11sh	11si	11sj	11sk	11sl	11sm	11sn	11so	11sp	11sq	11sr	11ss	11st	11su	11sv	11sw	11sx	11sy	11sz	11ta	11tb	11tc	11td	11te	11tf	11tg	11th	11ti	11tj	11tk	11tl	11tm	11tn	11to	11tp	11tq	11tr	11ts	11tt	11tu	11tv	11tw	11tx	11ty	11tz	11ua	11ub	11uc	11ud	11ue	11uf	11ug	11uh	11ui	11uj	11uk	11ul	11um	11un	11uo	11up	11uq	11ur	11us	11ut	11uu	11uv	11uw	11ux	11uy	11uz	11va	11vb	11vc	11vd	11ve	11vf	11vg	11vh	11vi	11vj	11vk	11vl	11vm	11vn	11vo	11vp	11vq	11vr	11vs	11vt	11vu	11vv	11vw	11vx	11vy	11vz	11wa	11wb	11wc	11wd	11we	11wf	11wg	11wh	11wi	11wj	11wk	11wl	11wm	11wn	11wo	11wp	11wq	11wr	11ws	11wt	11wu	11wv	11ww	11wx	11wy	11wz	11xa	11xb	11xc	11xd	11xe	11xf	11xg	11xh	11xi	11xj	11xk	11xl	11xm	11xn	11xo	11xp	11xq	11xr	11xs	11xt	11xu	11xv	11xw	11xx	11xy	11xz	11ya	11yb	11yc	11yd	11ye	11yf	11yg	11yh	11yi	11yj	11yk	11yl	11ym	11yn	11yo	11yp	11yq	11yr	11ys	11yt	11yu	11yv	11yw	11yx	11yy	11yz	11za	11zb	11zc	11zd	11ze	11zf	11zg	11zh	11zi	11zj	11zk	11zl	11zm	11zn	11zo	11zp	11zq	11zr	11zs	11zt	11zu	11zv	11zw	11zx	11zy	11zz
			10	Same tests and terminal conditions as subgroup 9, except $T_c = +125^\circ\text{C}$ and use limits from table I.																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																													
			11	Same tests, terminal conditions and limits as for subgroup 10, except $T_c = -55^\circ\text{C}$.																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																													

1/ For case 2 pins not referenced are N/C.
2/ I_{IL} limits shall be as follows:

Test	Min/Max limits in mA for circuit			
	A	B	C	D
I_{IL}	-0.25/-0.60	-0.03/-0.60	-0.03/-0.60	0.0/-0.30

3/ A = 2.5 V, B = 0.5 V, H ≥ 1.5 V, L ≤ 1.5 V.
4/ Perform function sequence at $V_{CC} = 4.5$ V and repeat at $V_{CC} = 5.5$ V.

TABLE III. Group A inspection for device type 08.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Limits		Measured terminal	Unit					
																				Min	Max							
1 Tc = 25°C	V _{OH}	3006	Case 2 1/ Test no.	1	OE a																							
				2	0.8 V	S1																						
				3	0.8 V																							
				4	2.0 V																							
				5	0.8 V																							
				6	0.8 V																							
				7	0.8 V																							
				8	2.0 V																							
				9	0.8 V																							
				10	0.8 V																							
				11	2.0 V																							
				12	2.0 V																							
				13	0.8 V																							
				14	0.8 V																							
				15	2.0 V																							
				16	2.0 V																							
	V _{OL}	3007	Test no.	17	-18 mA																							
				18	-18 mA																							
				19																								
				20	-18 mA																							
				21																								
				22	-18 mA																							
				23																								
				24																								
				25																								
				26																								
				27																								
				28																								
	I _{HI1}	3010	Test no.	29	2.7 V																							
				30	2.7 V																							
				31	0.0 V																							
				32	0.0 V																							
				33	4.5 V																							
				34																								
				35																								
				36																								
				37	0.0 V																							
				38	0.0 V																							
				39																								
				40																								
	I _{HI2}		Test no.	41	7.0 V																							
				42																								
				43	7.0 V																							
				44	0.0 V																							
				45	4.5 V																							
				46																								
				47																								
				48																								
				49	0.0 V																							
				50	0.0 V																							
				51																								
				52																								

See footnotes at end of table.

TABLE III. Group A inspection for device type 08 - Continued.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F	Terminal conditions																Measured terminal	Limits		Unit		
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		Min	Max			
1	I_{IL1}	3009	53	OE a	0.5 V														OE a	2/	2/	mA			
			54		0.5 V															S1	"	"	"	"	
			55		4.5 V	0.5 V														I3a	"	"	"	"	
			56		4.5 V															I2a	"	"	"	"	
			57		0.0 V															I1a	"	"	"	"	
			58					0.5 V												I0a	"	"	"	"	
			59																	I0b	"	"	"	"	
			60																	I1b	"	"	"	"	
			61																	I2b	"	"	"	"	
			62																	I3b	"	"	"	"	
			63																	S0	"	"	"	"	
			64																		OE b	0.5 V	"	"	
			65																		Za	-60	-150	"	
			66																		Zb	-60	-150	"	
67																		Za	35	"	"				
68																		Zb	35	"	"				
69																		Za	"	"	"				
70																		Zb	"	"	"				
71																		Za	50	"	"				
72																		Zb	50	"	"				
73																		Za	-50	"	"				
74																		Zb	-50	"	"				
75																		V _{CC}	23	"	"				
76																		V _{CC}	16	"	"				
77																		V _{CC}	23	"	"				
78																		V _{CC}	16	"	"				
79																		V _{CC}	23	"	"				
80																		V _{CC}	16	"	"				
81																		V _{CC}	23	"	"				
82																		V _{CC}	16	"	"				
83																		V _{CC}	23	"	"				
2	Same tests, terminal conditions, and limits as for subgroup 1, except $T_c = +125^\circ\text{C}$ and V_{IC} tests are omitted.																								
3	Same tests, terminal conditions, and limits as for subgroup 1, except $T_c = -55^\circ\text{C}$ and V_{IC} tests are omitted.																								
7	Functional test 3/	3014	76	B	B	B	B	L	GND	L	H	B	B	B	B	B	B	B	B	B	B	B	All outputs		
			77	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	
			78	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	
			79	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	
			80	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	
			81	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	
			82	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	
			83	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			84	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			85	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			86	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			87	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			88	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			89	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
90	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"			
91	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"			
92	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"			
93	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"			
94	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"			
95	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"			
96	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"			
97	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"			
98	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"			
99	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"			
8	Same tests, terminal conditions, and limits as for subgroup 7, except $T_c = +125^\circ\text{C}$ and $T_c = 55^\circ\text{C}$.																								
9	t_{PH1}	3003	84	0.0 V	0.0 V																		ns		
			85	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	
			86	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	
			87	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	
			88	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			89	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			90	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			91	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			92	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			93	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			94	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			95	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			96	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
			97	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
98	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"			
99	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"			

See footnotes at end of table.

TABLE III. Group A inspection for device type 10.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F Case 2 1/ Test no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured terminal	Limits		Unit			
				OE a	S1	I3a	I2a	I1a	I0a	Z a	GND	Z b	I0b	I1b	I2b	I3b	S0	OE b	Vcc		Min	Max				
1 Tc = 25°C	V _{OH}	3006	1	0.8 V	0.8 V				0.8 V	0.8 V							0.8 V		4.5 V	Z a	2.4		V			
			2	"	0.8 V			0.8 V											2.0 V			"	"	"	"	
			3	"	2.0 V		0.8 V												0.8 V				"	"	"	"
			4	"	2.0 V	0.8 V													2.0 V				"	"	"	"
			5	"	0.8 V														0.8 V	0.8 V			"	"	"	"
			6	"	0.8 V														2.0 V				"	"	"	"
			7	"	2.0 V														0.8 V				"	"	"	"
			8	"	2.0 V														0.8 V				"	"	"	"
	V _{OL}	3007	9	0.8 V	0.8 V				2.0 V	20 mA								0.8 V			Z a	0.5		"		
			10	"	0.8 V			2.0 V											2.0 V			"	"	"	"	
			11	"	2.0 V		2.0 V												0.8 V			"	"	"	"	
			12	"	2.0 V	2.0 V													2.0 V			"	"	"	"	
			13	"	0.8 V														0.8 V	0.8 V		Z b	"	"	"	"
			14	"	0.8 V														2.0 V			"	"	"	"	
			15	"	2.0 V														0.8 V			"	"	"	"	
			16	"	2.0 V														2.0 V			"	"	"	"	
	V _{IC}		17	-18 mA														2.0 V			OE a	-1.2		"		
			18		-18 mA																	S1	"	"	"	
			19																			I3a	"	"	"	
			20			-18 mA																I2a	"	"	"	
			21																			I1a	"	"	"	
			22																			I0a	"	"	"	
			23																			I0b	"	"	"	
			24																			I1b	"	"	"	
	I _{IH1}	3010	25																		I2b	"	"	"		
			26																			I3b	"	"	"	
			27																			S0	"	"	"	
			28																-18 mA	-18 mA		OE b	"	"	"	
			29		2.7 V																5.5 V	OE a	20		μA	
			30		2.7 V																	S1	"	"	"	
			31		4.5 V	0.0 V	2.7 V															I3a	"	"	"	
			32		"	0.0 V		2.7 V														I2a	"	"	"	
	I _{IH2}		33	"	4.5 V				2.7 V												I1a	"	"	"		
			34	"	"					2.7 V											I0a	"	"	"		
			35	"	"						2.7 V										I0b	"	"	"		
			36	"	"																I1b	"	"	"		
			37	"	0.0 V																	I2b	"	"	"	
			38	"	0.0 V																	I3b	"	"	"	
			39	"																		S0	"	"	"	
			40	"																		OE b	"	"	"	
	I _{IH2}		41	7.0 V																	OE a	100		"		
			42	"	7.0 V																	S1	"	"	"	
			43	"	4.5 V	0.0 V	7.0 V															I3a	"	"	"	
			44	"	"	0.0 V		7.0 V														I2a	"	"	"	
			45	"	"	4.5 V			7.0 V													I1a	"	"	"	
			46	"	"	4.5 V				7.0 V												I0a	"	"	"	

See footnotes at end of table.

TABLE III. Group A inspection for device type 10 - Continued.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F Case 2 $\frac{1}{1}$	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured terminal	Limits		Unit		
																					Min	Max			
1 Tc = 25°C	I _{Hz}	3010	OE a	OE a	I2a	I3a	I2a	I1a	I0a	Z a	GND	Z b	I0b	I1b	I2b	I3b	S0	OE b	OE b	I0b	100		μA		
			47	4.5 V																					
			48	4.5 V																					
			49	0.0 V																					
			50	0.0 V																					
			51																						
			52																						
			53	0.5 V																					
			54	0.5 V																					
			55	0.0 V	0.5 V																				
			56	4.5 V	0.5 V																				
			57	0.0 V																					
58																									
59																									
60																									
61																									
62																									
63																									
64																									
65	2.0 V																								
66																									
67	2.0 V																								
68																									
69	0.0 V																								
70	0.0 V																								
71	0.0 V																								
72	0.0 V																								
73	0.0 V																								
74	0.0 V																								
75	4.5 V																								
2	Same tests, terminal conditions, and limits as subgroup 1, except T _c = +125°C and V _{IC} tests are omitted.																								
3	Same tests, terminal conditions, and limits as subgroup 1, except T _c = -55°C and V _{IC} tests are omitted.																								
7 Tc = 25°C	Functional test $\frac{3}{3}$	3014	B	B	B	B	B	B	B	H	GND	H	B	B	B	B	B	B	B	B	B	B	All outputs		
			76																						
			77																						
			78																						
			79																						
			80																						
			81																						
			82																						
			83																						
			84																						
			85																						
			86																						
87																									
88																									
89																									
90																									
91																									
8	Same tests, terminal conditions, and limits as for subgroup 7, except T _c = +125°C and T _c = -55°C.																								

See footnotes at end of table.

TABLE III. Group A inspection for device type 10 - Continued.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F	Terminal conditions																Limits		Unit							
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Min	Max								
9 T _c = 25°C	t _{PHL2}	3003 Fig. 4	Case 2	Case 2	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	1.5	7.0	ns						
			Test no.	Test no.	OE a	S1	I3a	I2a	I1a	I0a	Z a	GND	GND	Z b	I0b	I1b	I2b	I3b	S0	OE b	V _{cc}	5.0 V							
			92	93	0.0 V	2.7 V	IN	IN																					
			94	95	"	2.7 V			IN																				
			96	97	"	0.0 V				IN																			
			98	99	"	"																							
			100	101	"	2.7 V																							
			102	103	"	0.0 V																							
			104	105	"	"																							
			106	107	"	2.7 V																							
			108	109	"	0.0 V																							
			110	111	"	2.7 V																							
			112	113	"	0.0 V																							
			114	115	"	0.0 V																							
			116	117	"	IN																							
			118	119	"	IN																							

See footnotes at end of table.

TABLE III. Group A inspection for device type 10 - Continued.
Terminal conditions (pins not designated may be high ≥ 2.0 V; low ≤ 0.8 V; or open).

Subgroup	Symbol	MIL-STD-883 method	Cases E, F	Pins																Measured terminal	Limits		Unit
				1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		Min	Max	
9 $T_C = 25^\circ\text{C}$	t_{PZL6}	3003	Test no. 120	OE a	S1	13a	12a	11a	10a	Z a	GND	Z b	10b	11b	12b	13b	S0	OE b	5.0 V	3.0	11.0	ns	
	t_{PZH6}	Fig. 4	121	IN	"	"	"	"	2.7 V	OUT	"	OUT	2.7 V	"	"	"	IN	"	"	3.0	11.0	"	
			122	IN	"	"	"	"	0.0 V	OUT	"	OUT	0.0 V	"	"	"	"	"	"	"	3.0	8.0	"
123	IN	"	"	"	"	"	"	"	"	"	OUT	0.0 V	"	"	"	IN	"	"	"	3.0	8.0	"	
10	Same tests and terminal conditions as subgroup 9, except $T_C = +125^\circ\text{C}$ and for the following limits. $t_{PHL2} = 1.5$ to 9.0 ns $t_{PHL3} = 1.5$ to 7.5 ns $t_{PZL6} = 3.5$ to 15.5 ns $t_{PLH4} = 4.0$ to 16.0 ns $t_{PHL4} = 4.0$ to 14.0 ns $t_{PZH6} = 2.0$ to 6.5 ns $t_{PZH6} = 3.0$ to 11.0 ns																						
11	Same tests, terminal conditions and limits as for subgroup 10, except $T_C = -55^\circ\text{C}$.																						

1/ For case 2 pins not referenced are N/C.
2/ I_{IL} limits shall be as follows:

Test	Min/Max limits in mA for circuit		
	A	B	C
I _{IL}	-0.25/- .60	-0.03/- .60	-0.03/- .60

3/ A = 2.5 V, B = 0.5 V, H ≥ 1.5 V, L ≤ 1.5 V.
4/ Perform function sequence at $V_{CC} = 4.5$ V and repeat at $V_{CC} = 5.5$ V.

5. PACKAGING

5.1 Packaging requirements. For acquisition purposes, the packaging requirements shall be as specified in the contract or order (see 6.2). When actual packaging of materiel is to be performed by DoD or in-house contractor personnel, these personnel need to contact the responsible packaging activity to ascertain packaging requirements. Packaging requirements are maintained by the Inventory Control Point's packaging activity within the Military Service or Defense Agency, or within the military service's system command. Packaging data retrieval is available from the managing Military Department's or Defense Agency's automated packaging files, CD-ROM products, or by contacting the responsible packaging activity.

6. NOTES

6.1 Intended use. Microcircuits conforming to this specification are intended for original equipment design applications and logistic support of existing equipment.

6.2 Acquisition requirements. Acquisition documents should specify the following:

- a. Title, number, and date of the specification.
- b. PIN and compliance identifier, if applicable (see 1.2).
- c. Requirements for delivery of one copy of the conformance inspection data pertinent to the device inspection lot to be supplied with each shipment by the device manufacturer, if applicable.
- d. Requirements for certificate of compliance, if applicable.
- e. Requirements for notification of change of product or process to contracting activity in addition to notification to the qualifying activity, if applicable.
- f. Requirements for failure analysis (including required test condition of method 5003 of MIL-STD-883), corrective action, and reporting of results, if applicable.
- g. Requirements for product assurance options.
- h. Requirements for special carriers, lead lengths, or lead forming, if applicable. These requirements should not affect the part number. Unless otherwise specified, these requirements will not apply to direct purchase by or direct shipment to the Government.
- i. Requirements for "JAN" marking.
- j. Packaging requirements (see 5.1).

6.3 Superseding information. The requirements of MIL-M-38510 have been superseded to take advantage of the available Qualified Manufacturer Listing (QML) system provided by MIL-PRF-38535. Previous references to MIL-M-38510 in this document have been replaced by appropriate references to MIL-PRF-38535. All technical requirements now consist of this specification and MIL-PRF-38535. The MIL-M-38510 specification sheet number and PIN have been retained to avoid adversely impacting existing government logistics systems and contractor's parts lists.

6.4 Qualification. With respect to products requiring qualification, awards will be made only for products which are, at the time of award of contract, qualified for inclusion in Qualified Manufacturers List QML-38535 whether or not such products have actually been so listed by that date. The attention of the contractors is called to these requirements, and manufacturers are urged to arrange to have the products that they propose to offer to the Federal Government tested for qualification in order that they may be eligible to be awarded contracts or purchase orders for the products covered by this specification. Information pertaining to qualification of products may be obtained from DSCC-VQ, 3990 E. Broad Street, Columbus, Ohio 43123-1199.

6.5 Abbreviations, symbols, and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-PRF-38535, MIL-HDBK-1331, and as follows:

GND Ground zero voltage potential
 I_{IN} Current flowing into an input terminal
 V_{IN} Voltage level at an input terminal

6.6 Logistic support. Lead materials and finishes (see 3.4) are interchangeable. Unless otherwise specified, microcircuits acquired for Government logistic support will be acquired to device class B (see 1.2.2), lead material and finish A (see 3.4). Longer length leads and lead forming should not affect the part number.

6.7 Substitutability. The cross-reference information below is presented for the convenience of users. Microcircuits covered by this specification will functionally replace the listed generic-industry type. Generic-industry microcircuit types may not have equivalent operational performance characteristics across military temperature ranges or reliability factors equivalent to MIL-M-35810 device types and may have slight physical variations in relation to case size. The presence of this information should not be deemed as permitting substitution of generic-industry types for MIL-M-38510 types or as a waiver of any of the provisions of MIL-PRF-38535.

Military device type	Generic-industry type
01	54F151A
02	54F153
03	54F157A
04	54F158A
05	54F251A
06	54F257A
07	54F258A
08	54F253
09	54F352
10	54F353

6.8 Manufacturers' designation. Manufacturers' circuits which form a part of this specification are designated with an "X" as shown in table IV herein.

TABLE IV. Manufacturers' designations.

Device type	Circuits			
	A	B	C	D
	National Semiconductor/ Fairchild Semiconductor	Motorola Inc.	Signetics Corp.	Texas Instruments
01	X	X		
02	X	X		X
03	X			X
04	X			
05	X	X		
06	X			X
07	X			
08	X	X		X
09		X		
10		X		

6.9 Changes from previous issue. Asterisks are not used in this revision to identify changes with respect to the previous issue due to the extensiveness of the changes.

CONCLUDING MATERIAL

Custodians:
Army - CR
Navy - EC
Air Force - 11
DLA - CC

Preparing activity:
DLA - CC
(Project 5962-2018)

Review activities:
Army - MI, SM
Navy - AS, CG, MC, SH, TD
Air Force - 03, 19, 99

NOTE: The activities listed above were interested in this document as of the date of this document. Since organizations and responsibilities can change, you should verify the currency of the information above using the ASSIST Online database at www.dodssp.daps.mil.